

# WORCESTER POLYTECHNIC INSTITUTE MECHANICAL ENGINEERING DEPARTMENT

Optical Metrology and NDT  
ME-593n/ ME-5304, C'2025

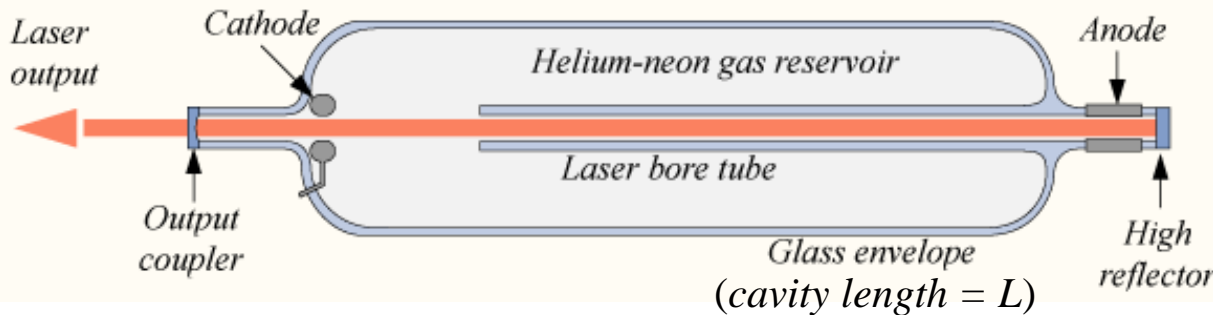
Lecture 03  
January 2025



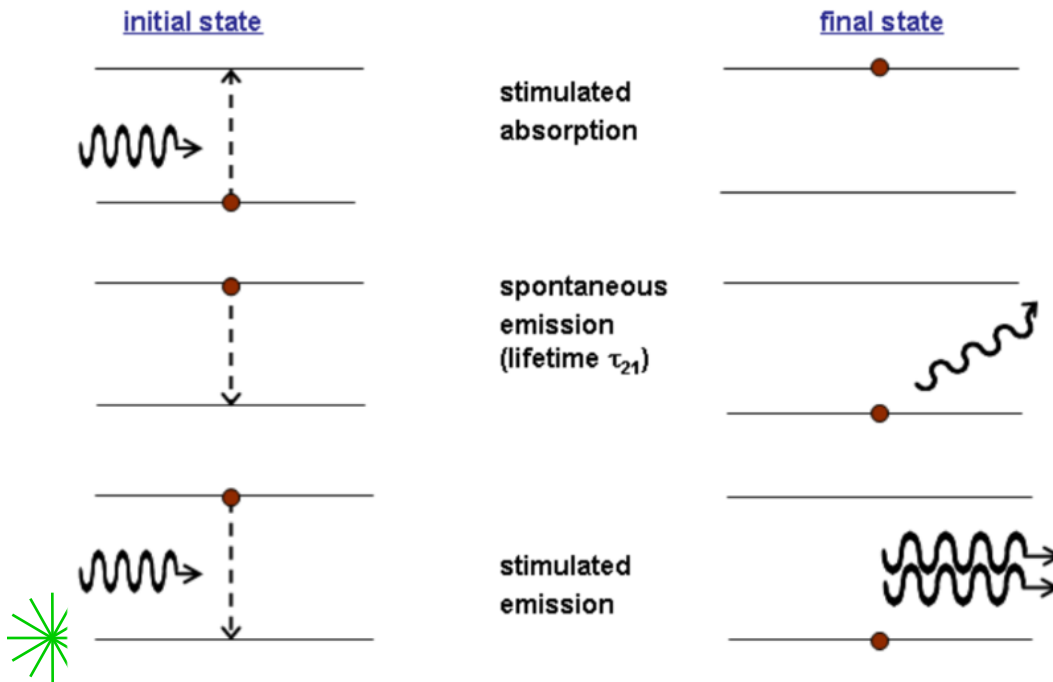
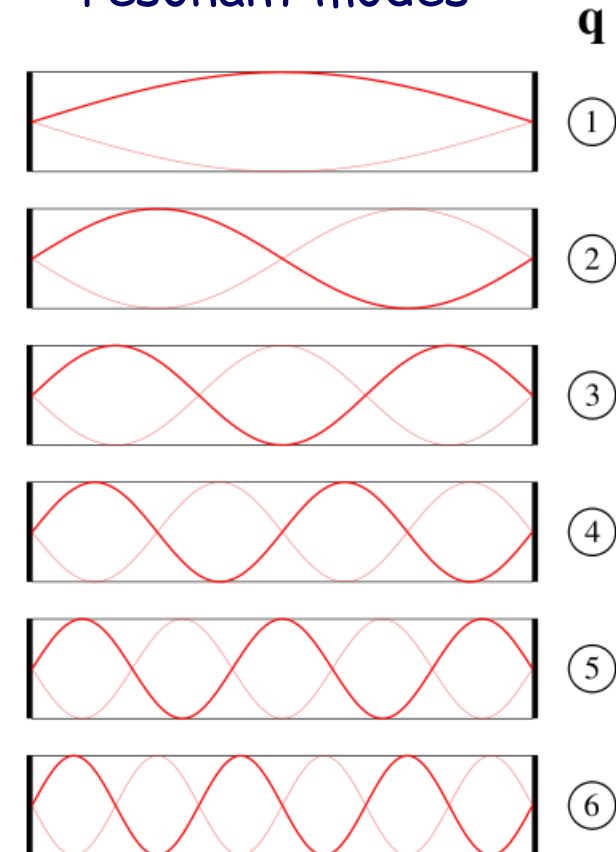
# Lasers sources

## Some operating characteristics: *laser modes*

### Schematic diagram of a He-Ne laser



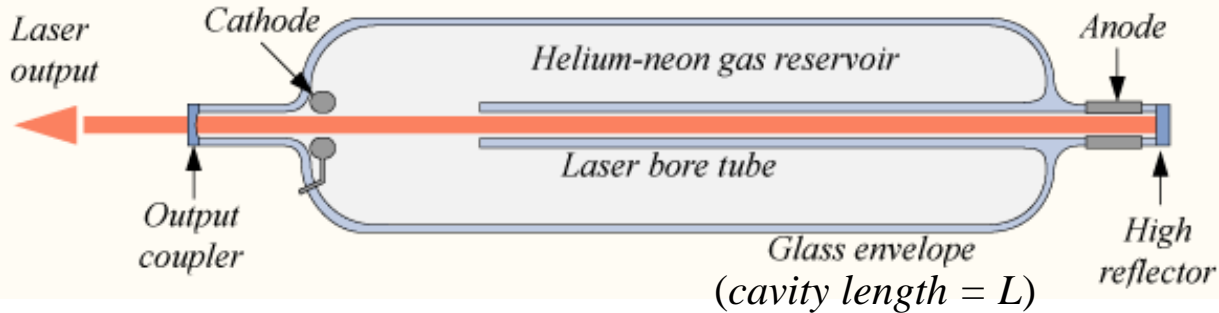
### Possible longitudinal resonant modes



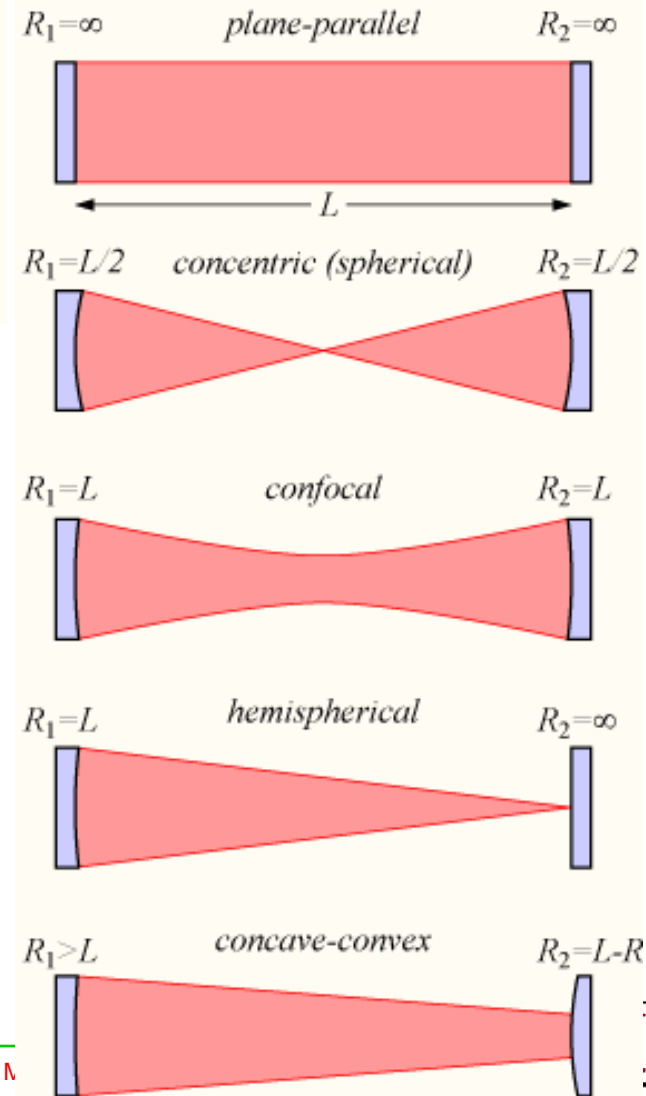
# Lasers sources

## Some operating characteristics: *laser modes*

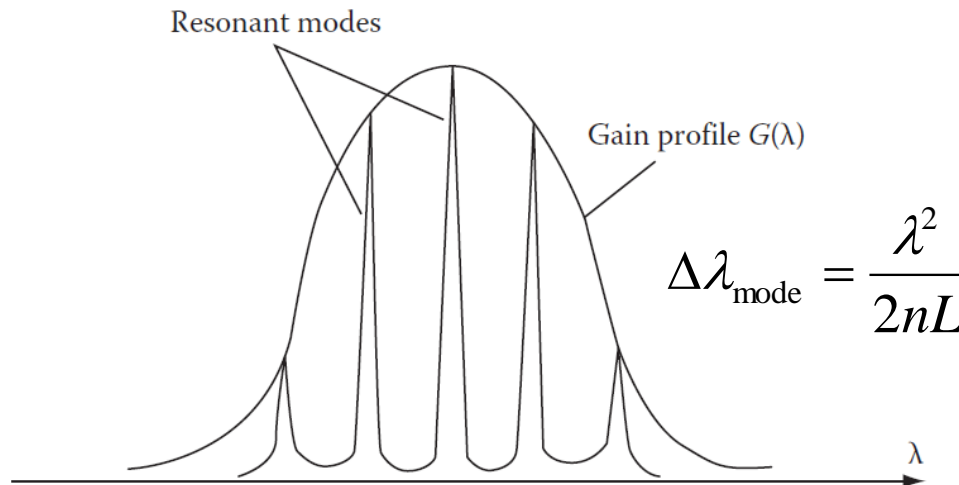
### Schematic diagram of a He-Ne laser



### Laser cavity configurations



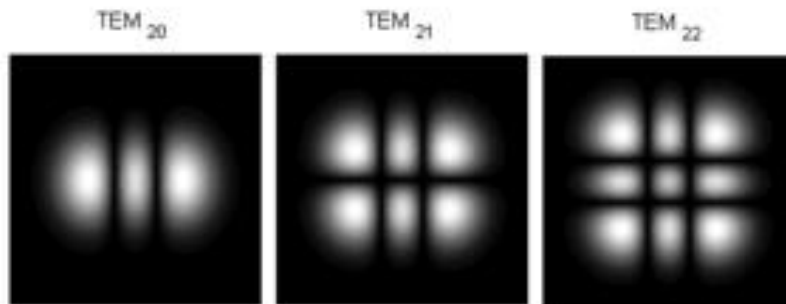
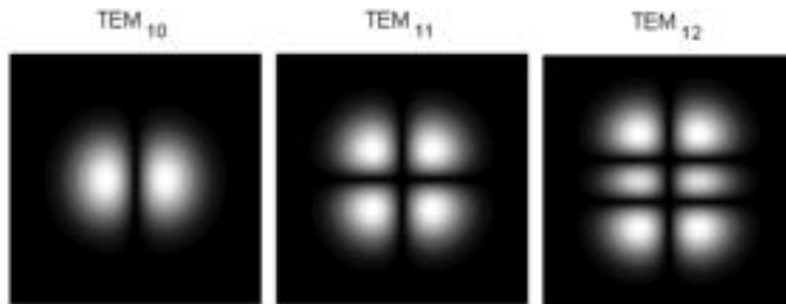
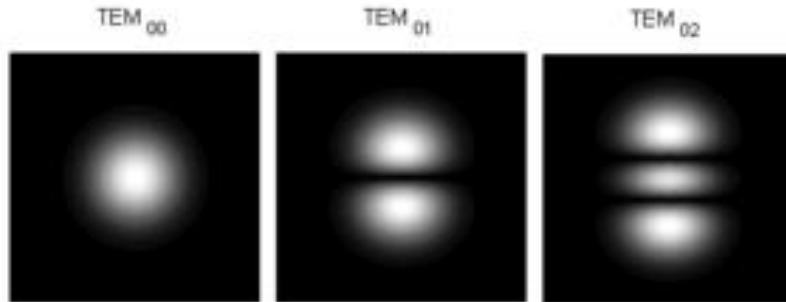
### Possible longitudinal resonant modes



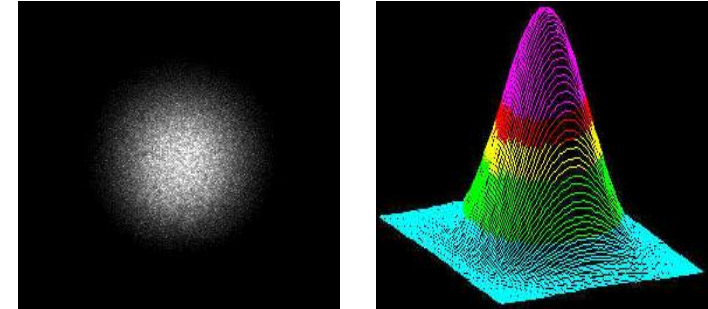
# Lasers sources

Some operating characteristics: *laser modes*

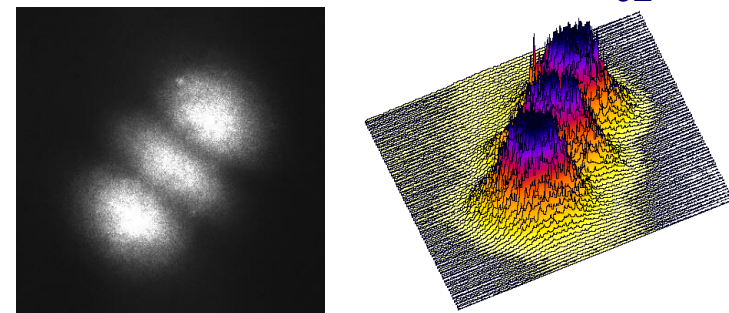
Possible transversal resonant modes



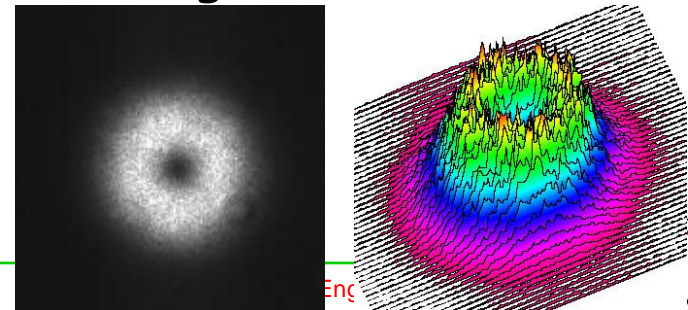
Gaussian TEM<sub>00</sub>



Hermite-Gaussian TEM<sub>02</sub>



Laguerre-Gaussian



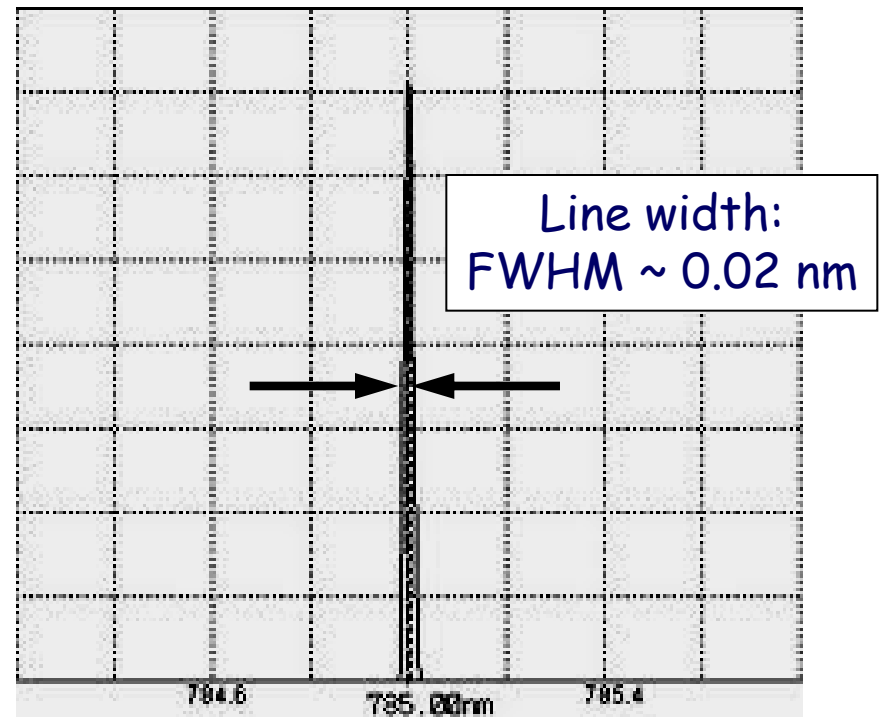
# Lasers sources

Some operating characteristics: *continuous & pulsed*

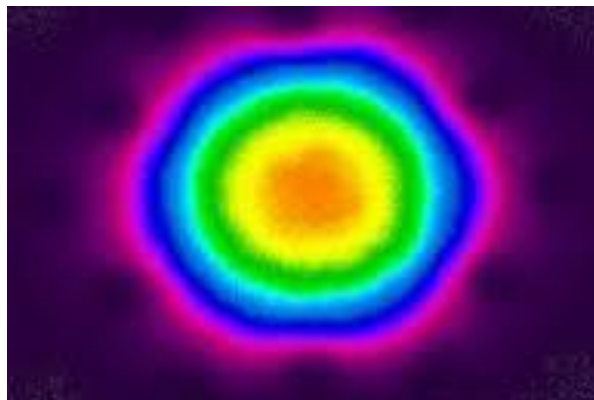
Near IR continuous laser



Output wavelength:  
narrow bandwidth



Transversal mode

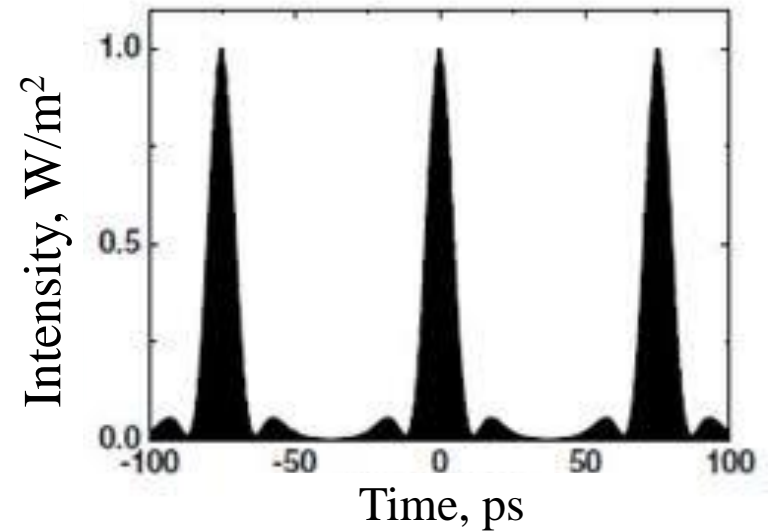


# Lasers sources

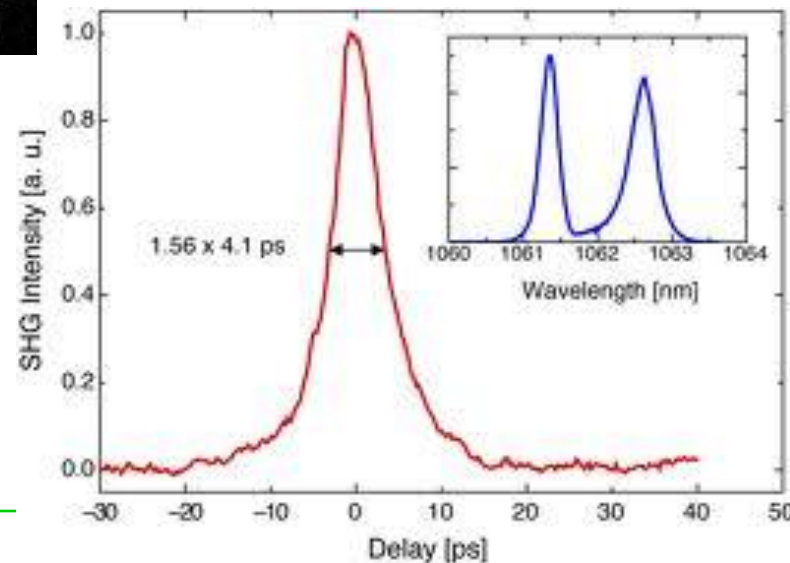
Some operating characteristics: *continuous & pulsed*

Picosecond **pulsed** laser

Typical pulsetrain



Individual pulse characteristics





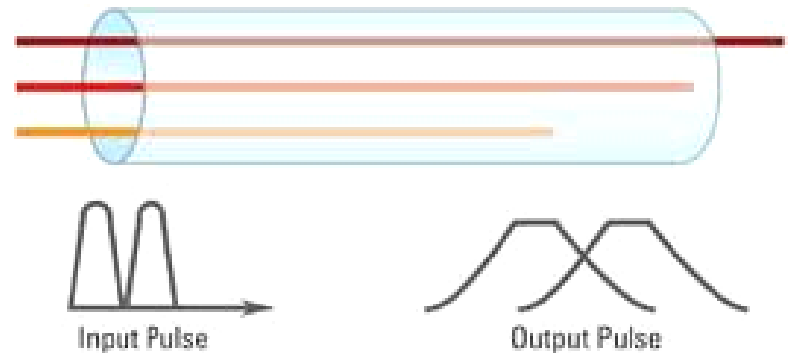
# Lasers sources

Some operating characteristics: *continuous & pulsed*

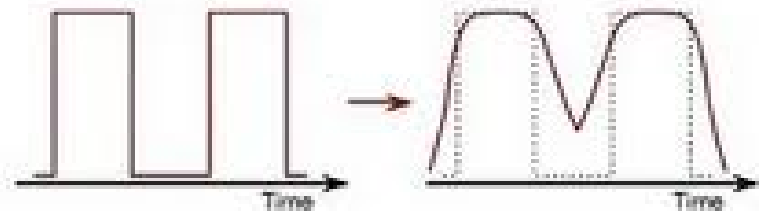
Picosecond **pulsed** laser



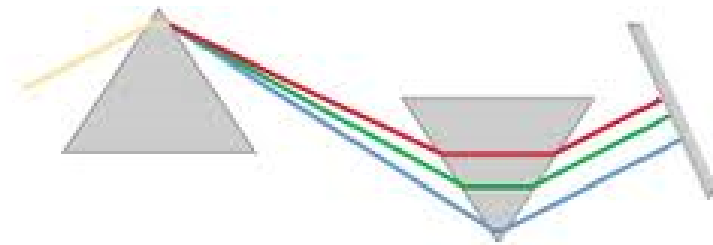
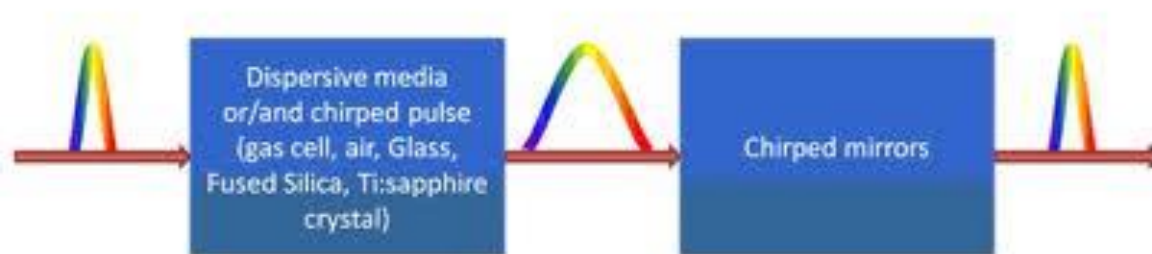
Pulse dispersion through media



Dispersion in optical fibers



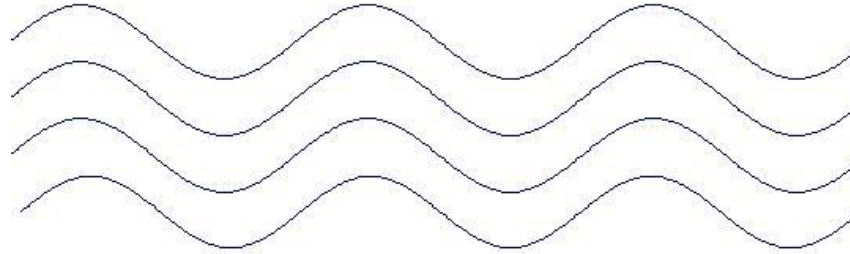
Dispersion compensation



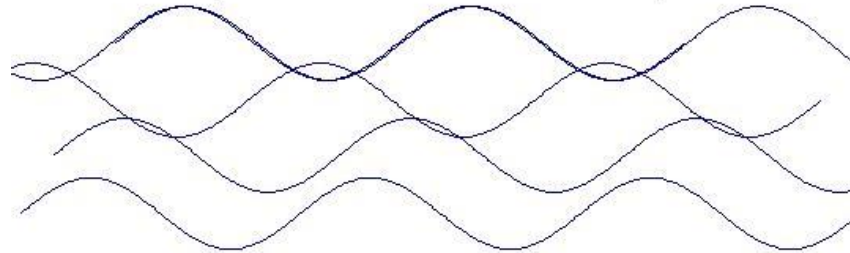
# Lasers sources

Some operating characteristics: *temporal coherence*

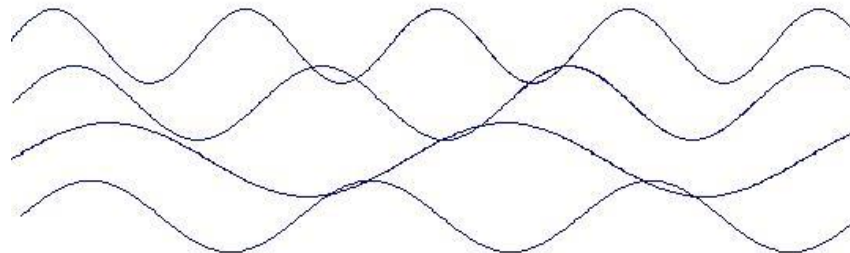
**Coherent Waves**



**Incoherent Waves  
(but still monochromatic)**



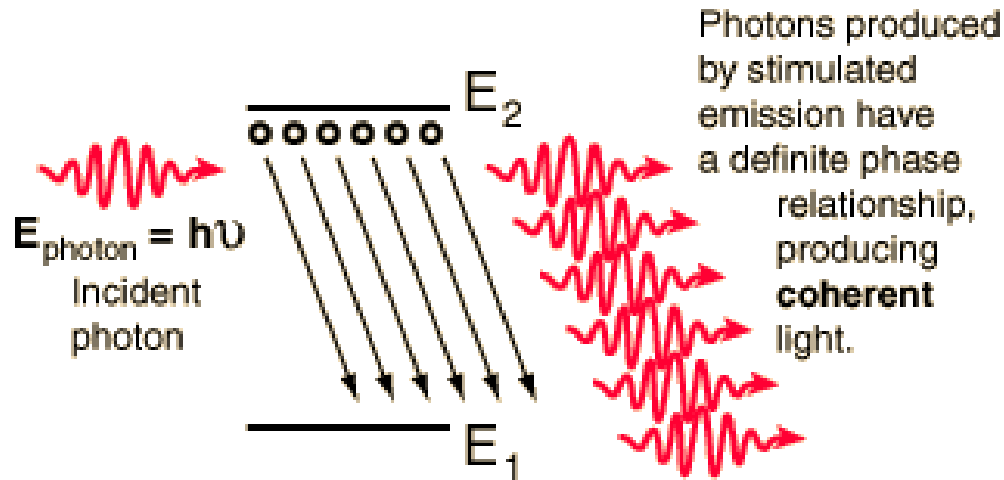
**Incoherent Waves  
of multiple frequencies**





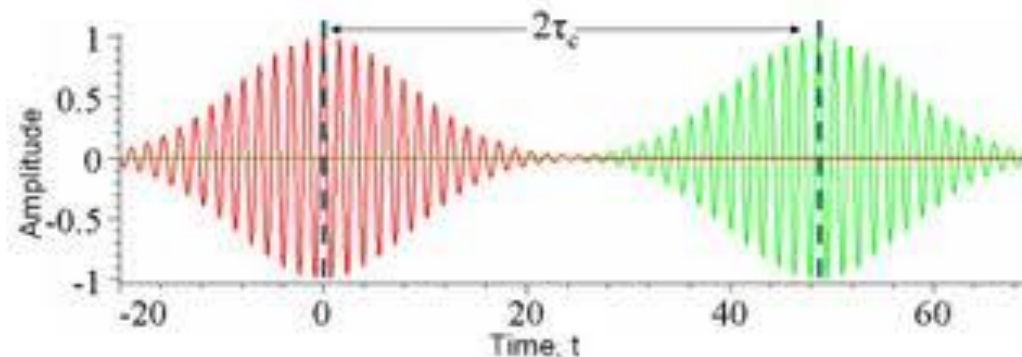
# Lasers sources

Some operating characteristics: *temporal coherence*



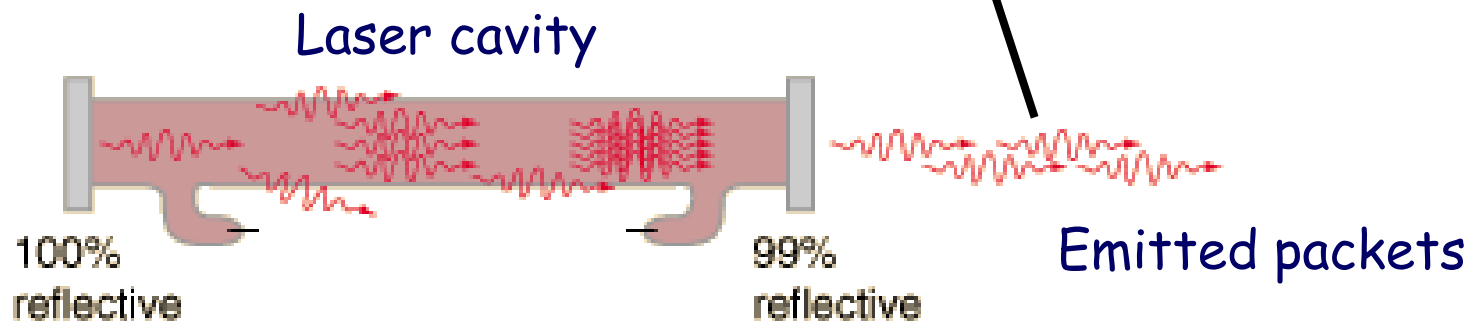
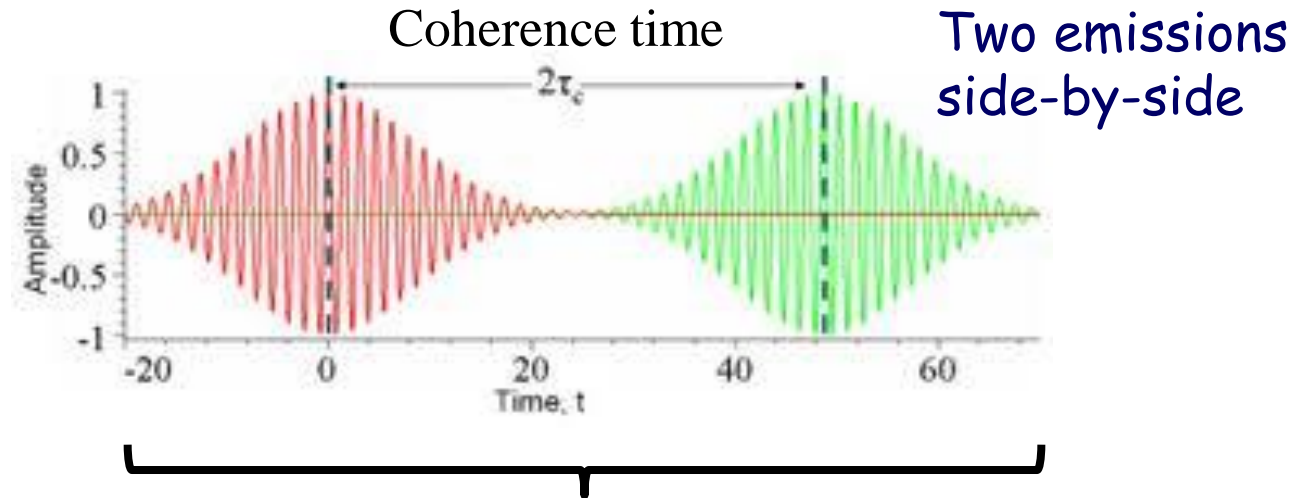
## Packets of emitted light

(Coherence time)



# Lasers sources

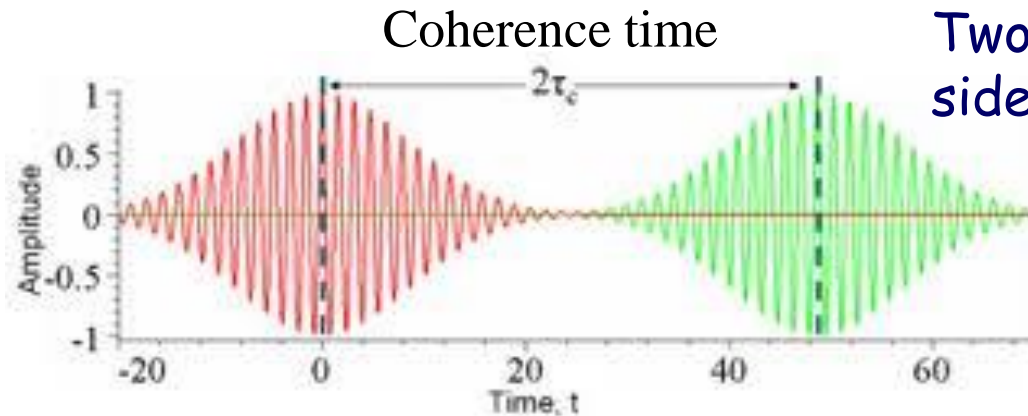
Some operating characteristics: *temporal coherence*



# Lasers sources

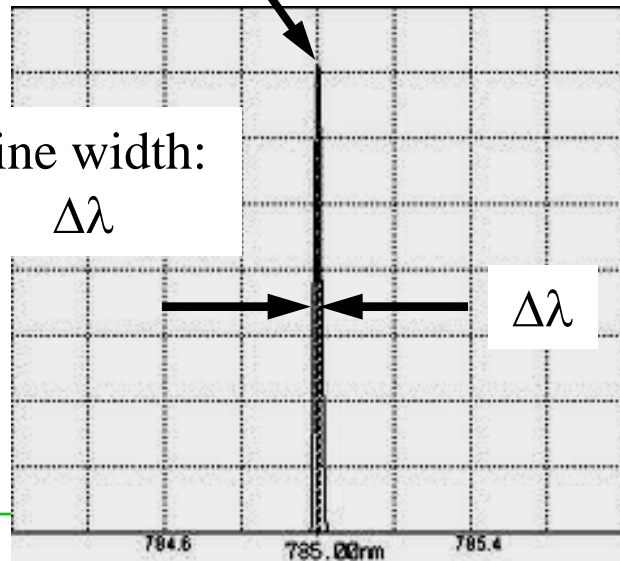
Some operating characteristics: *temporal coherence*

Temporal coherence length contributes to interference ability



Central wavelength:  $\lambda$

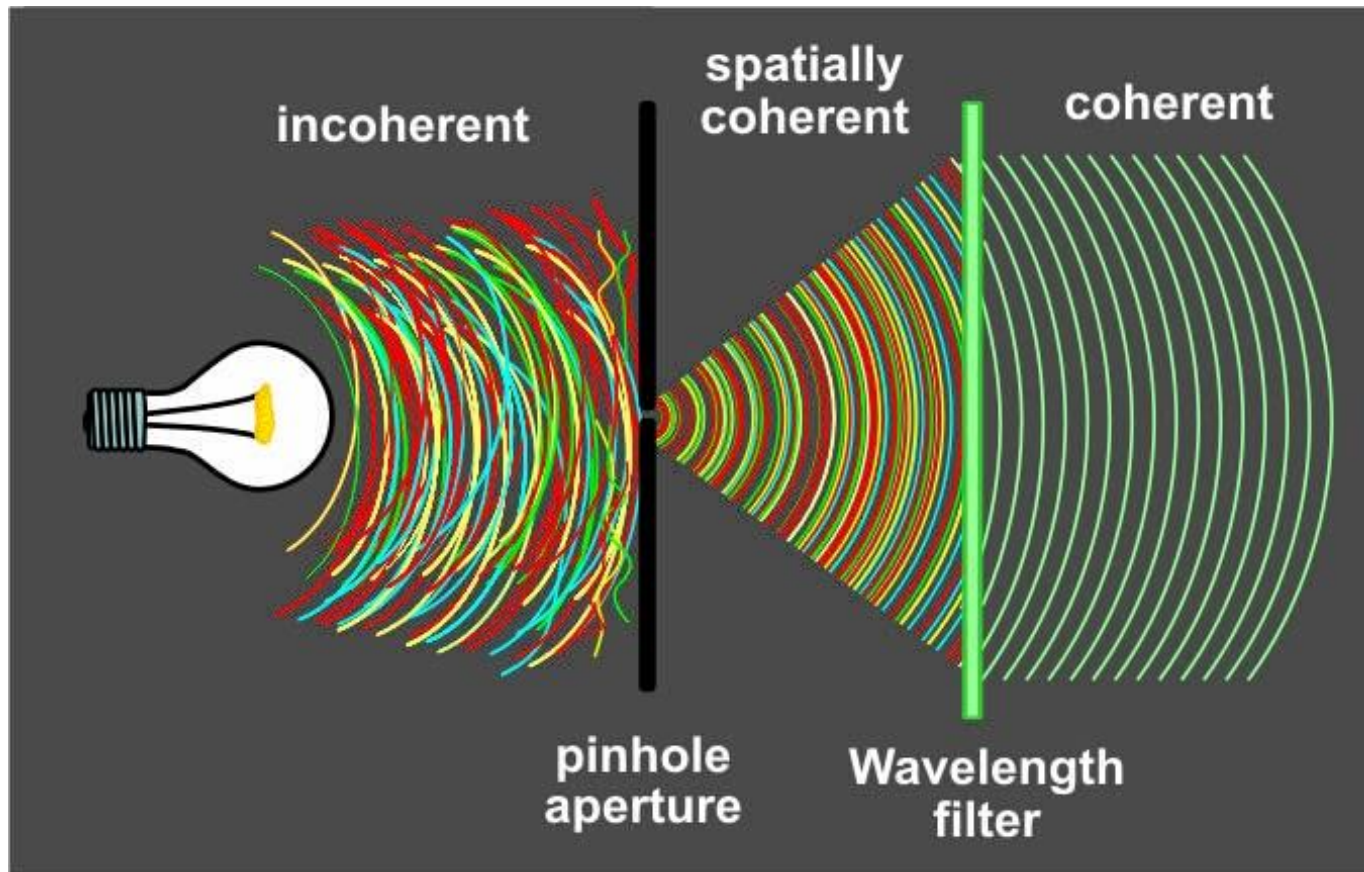
Line width:  
 $\Delta\lambda$



Coherence length:  $l_c = \sqrt{\frac{2 \cdot \ln(2)}{\pi}} \frac{\lambda^2}{\Delta\lambda}$

# Lasers sources

Some operating characteristics: *spatial coherence*

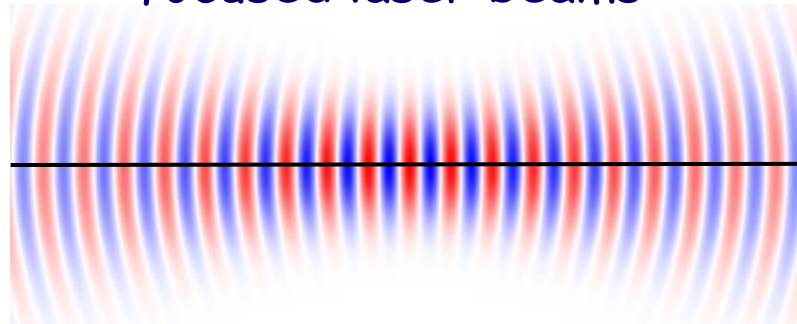


# Lasers sources

Some operating characteristics: *temporal & spatial coherence*

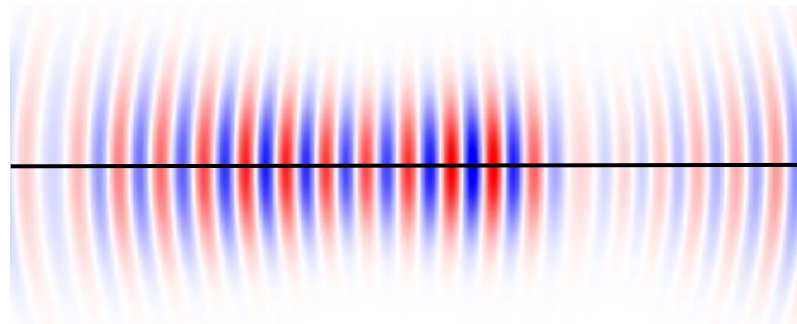
Electric fields of  
focused laser beams

Good temporal  
&  
Good spatial  
coherence



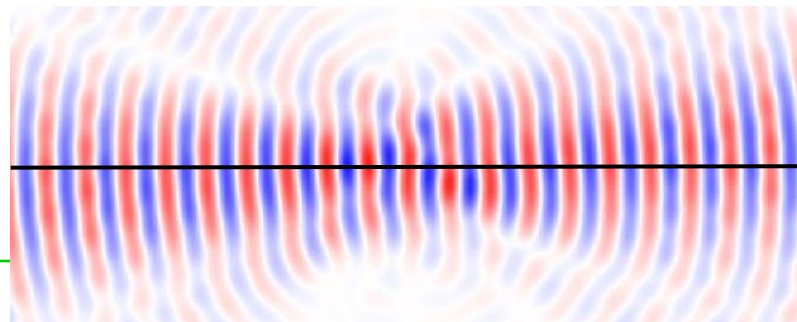
$z$  (Propagation  
direction)

Poor temporal  
&  
Good spatial  
coherence



$z$

Good temporal  
&  
Poor spatial  
coherence



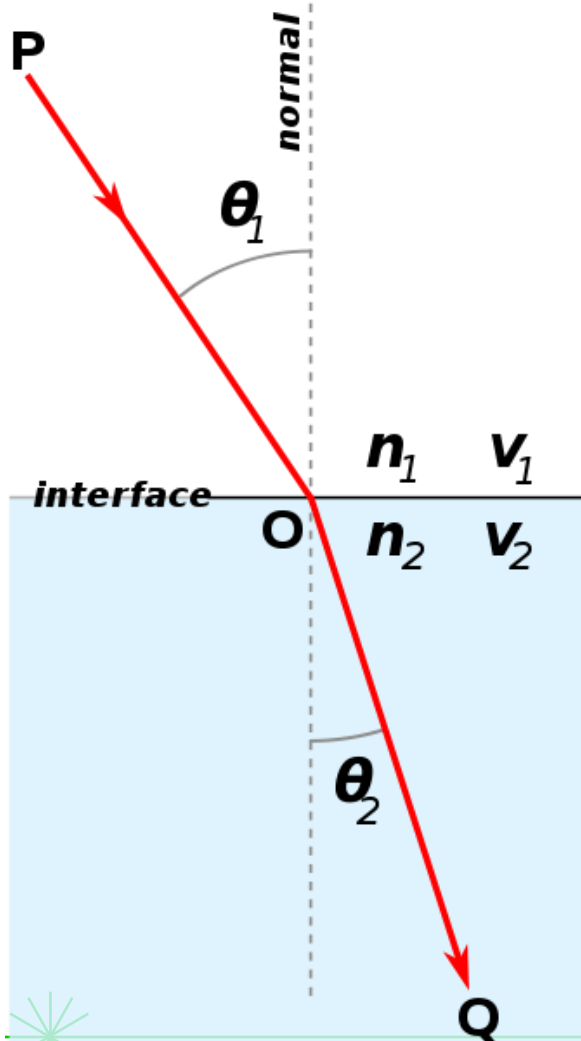
$z$



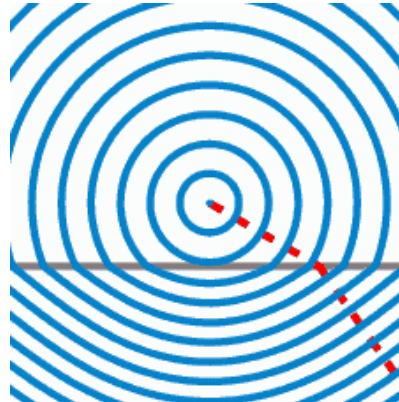
# Lenses

## Snell's law

Light ray propagating through two media



- $n_1$  and  $n_2$  are refractive indexes
- $v_1$  and  $v_2$  are velocities of light



Light wavefronts

$$n_1 \cdot \sin \theta_1 = n_2 \cdot \sin \theta_2$$

and

$$\frac{\sin \theta_1}{\sin \theta_2} = \frac{v_1}{v_2} = \frac{n_2}{n_1}$$

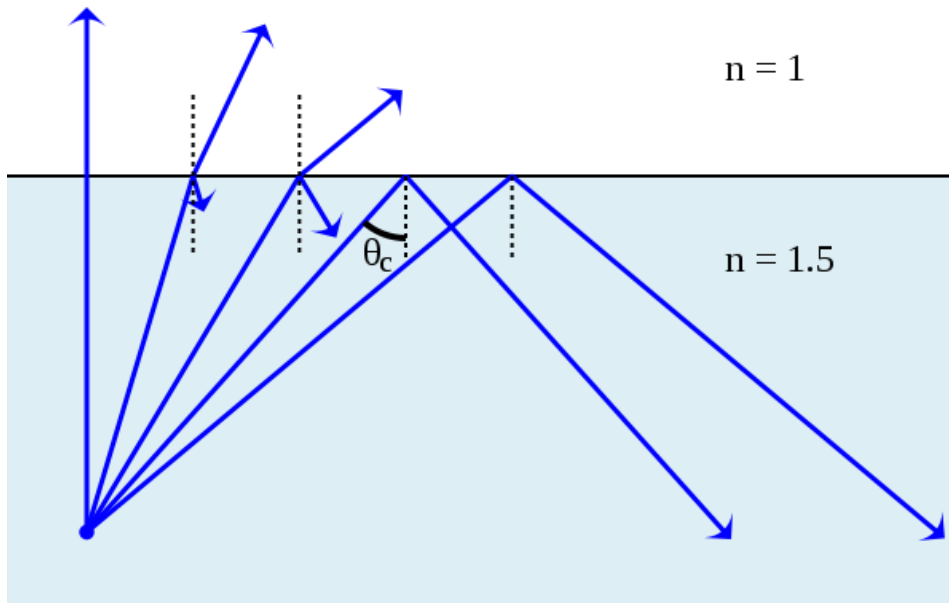




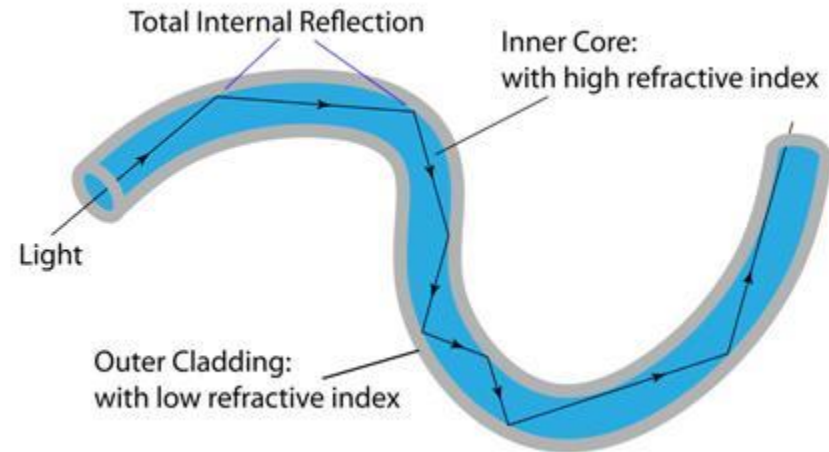
# Lenses

## Snell's law & total internal reflection

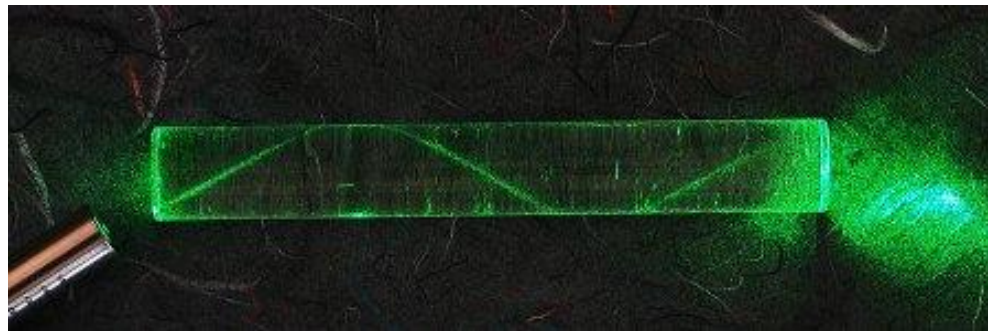
Angle of incidence and internal reflections:



## Fiber optics

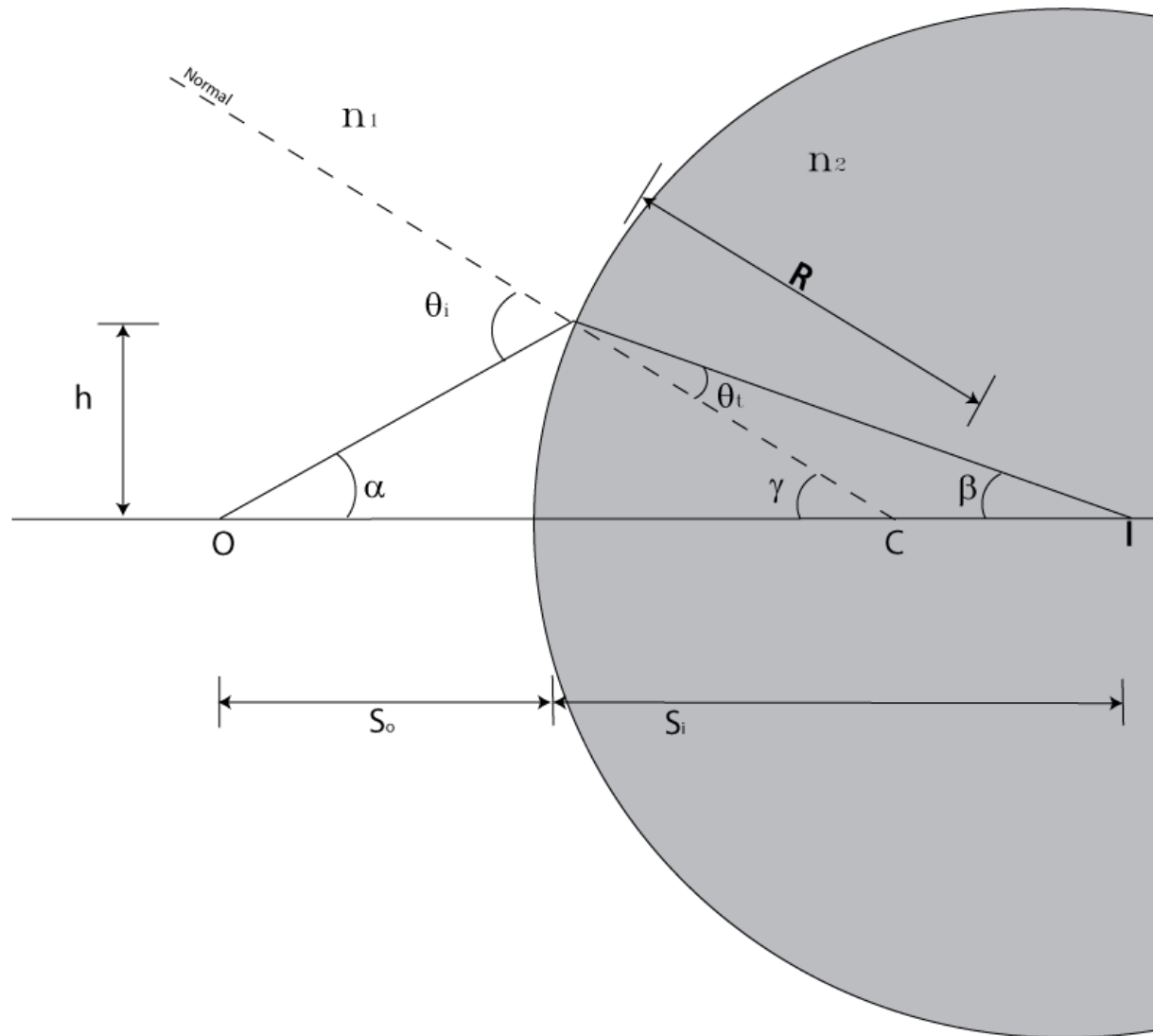


## Laser in fiber



# Lenses

Snell's law: refraction at a spherical interface



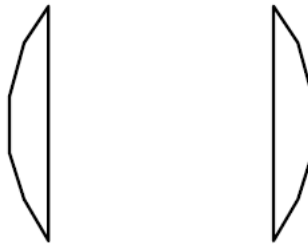
# Lenses

## Types

### Convergent lenses



double convex



planoconvex

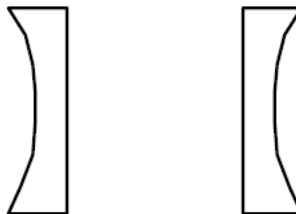


convex meniscus

### Divergent lenses



double concave



planoconcave



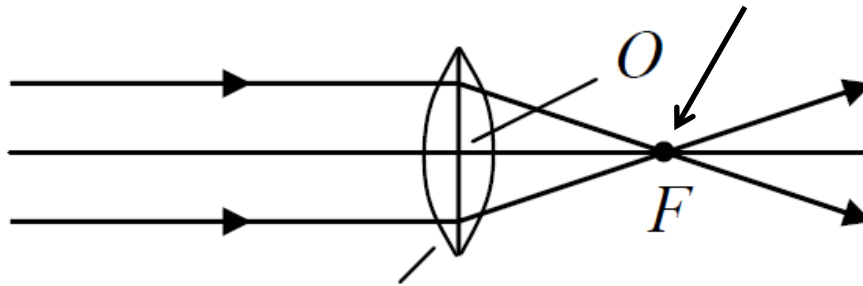
concave meniscus



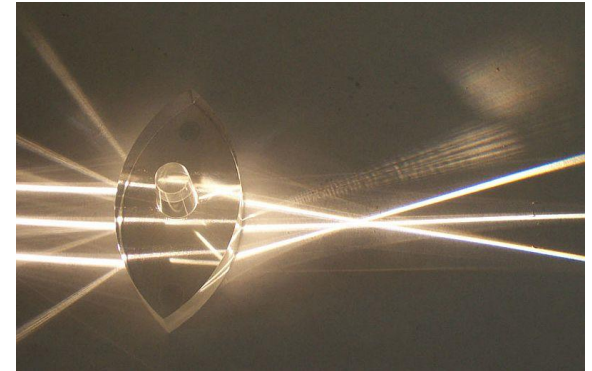
# Lenses

## Types

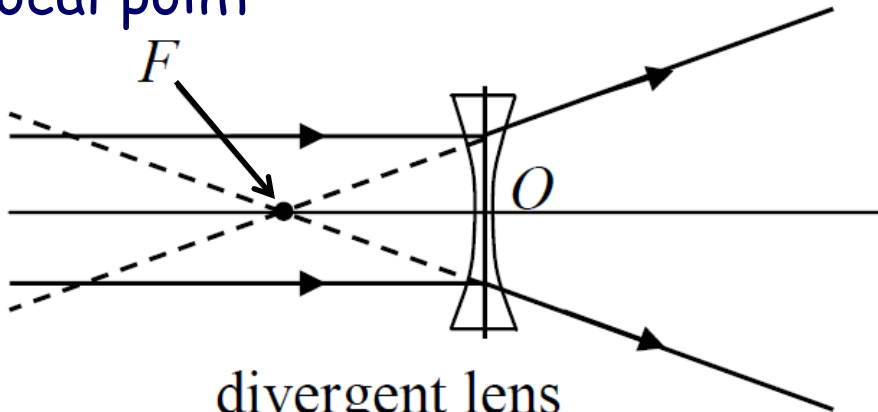
Focal point



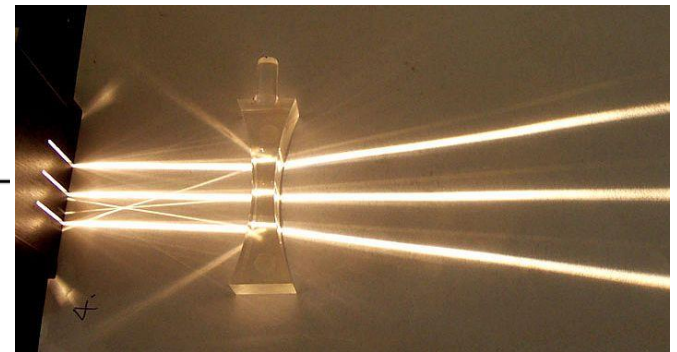
convergent lens  
( $f = \overline{OF} > 0$ )



Virtual focal point



divergent lens  
( $f = -\overline{OF} < 0$ )

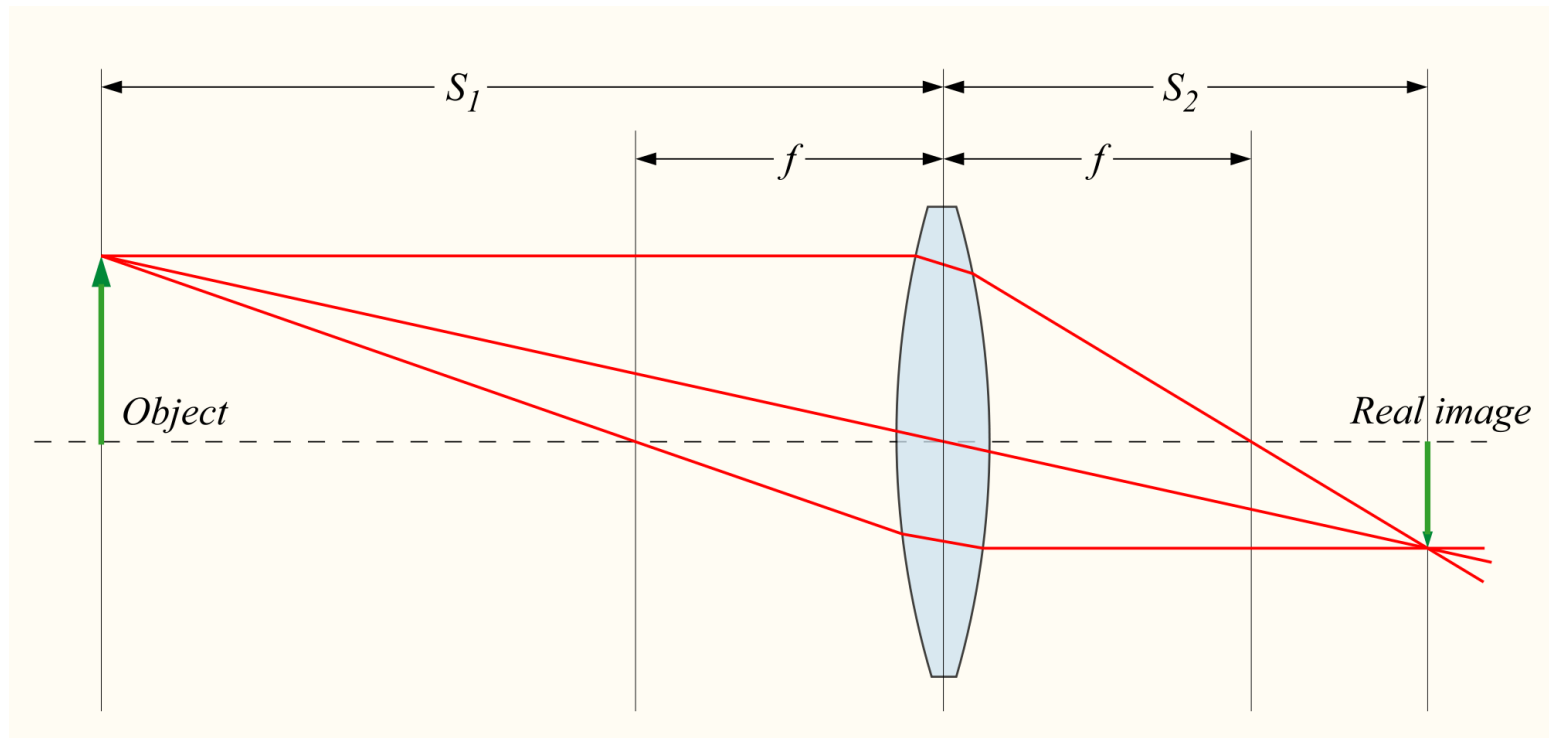


# Lenses

## Imaging properties: real image

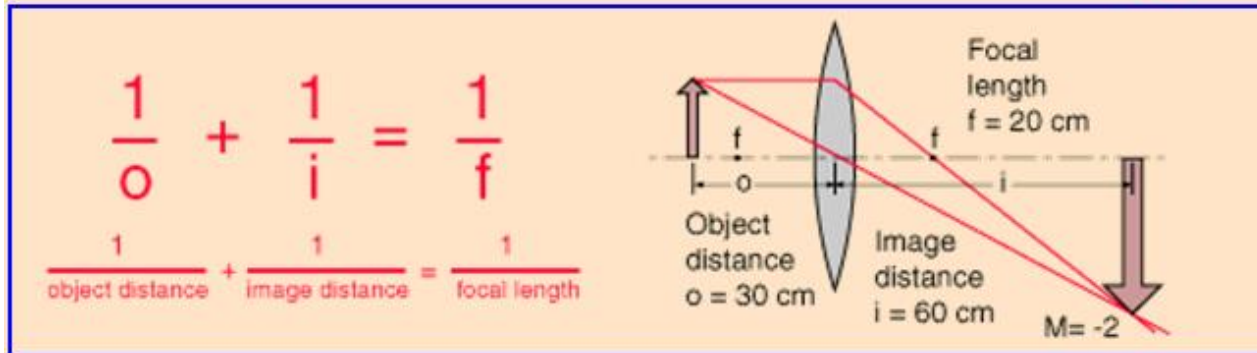
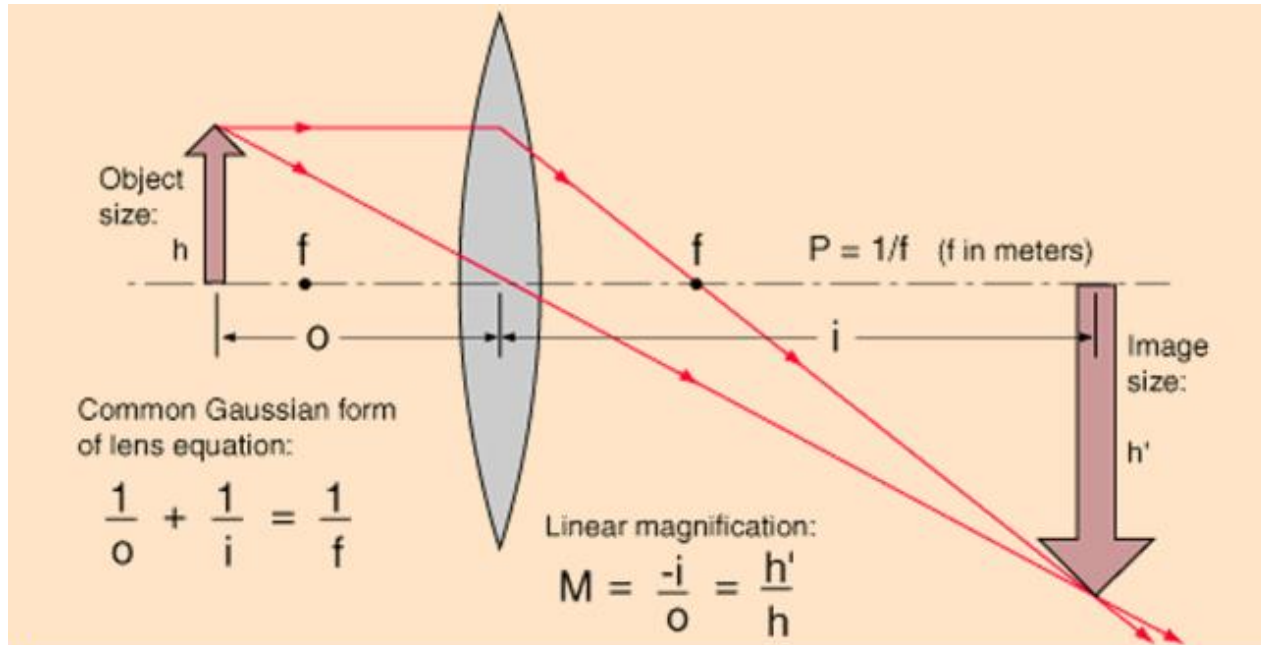
$$\frac{1}{S_1} + \frac{1}{S_2} = \frac{1}{f};$$

$$\text{Magnification: } M = -\frac{S_2}{S_1} = \frac{f}{f - S_1}$$



# Lenses

## Imaging properties: real image formation

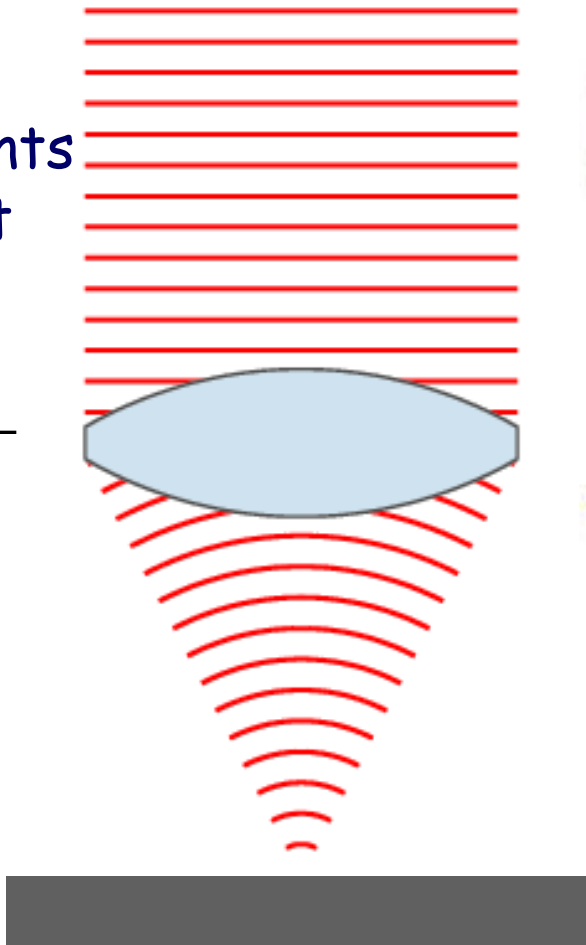
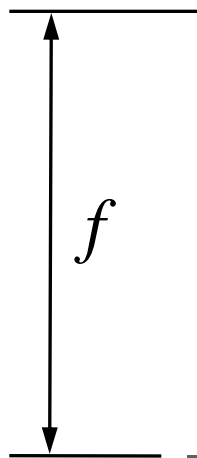




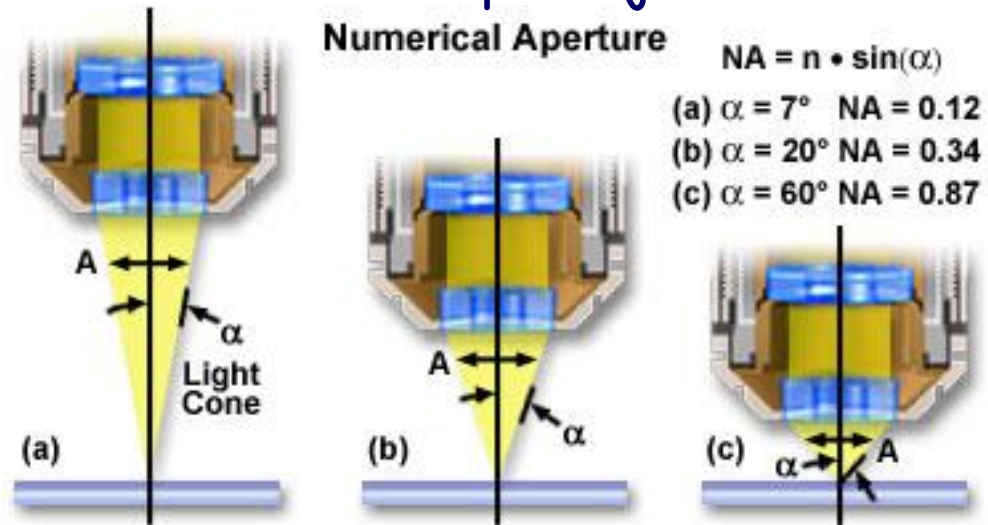
# Lenses

Imaging properties: real image formation

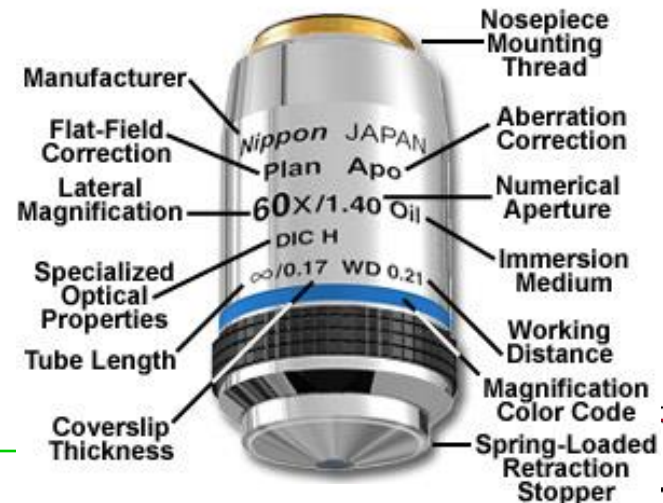
Wavefronts  
of light



## Microscope objectives



60x Plan Apochromat Objective

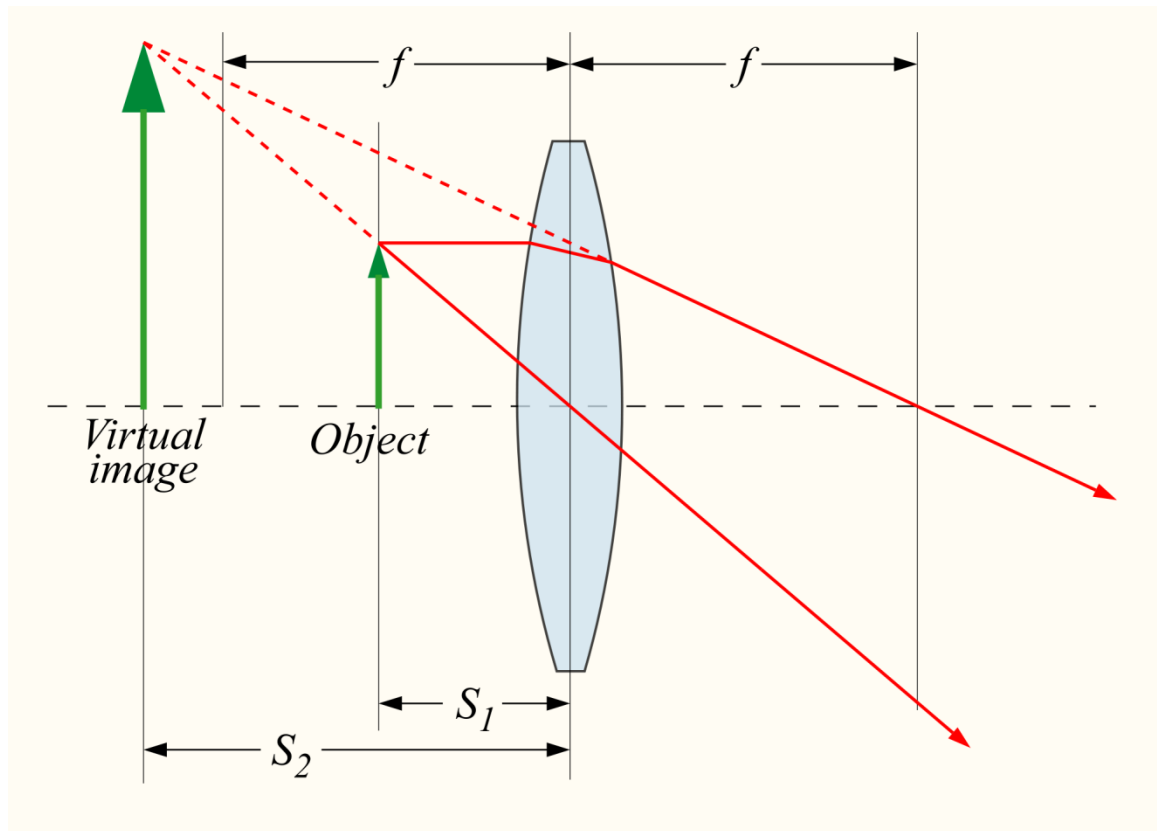


# Lenses

## Imaging properties: virtual image

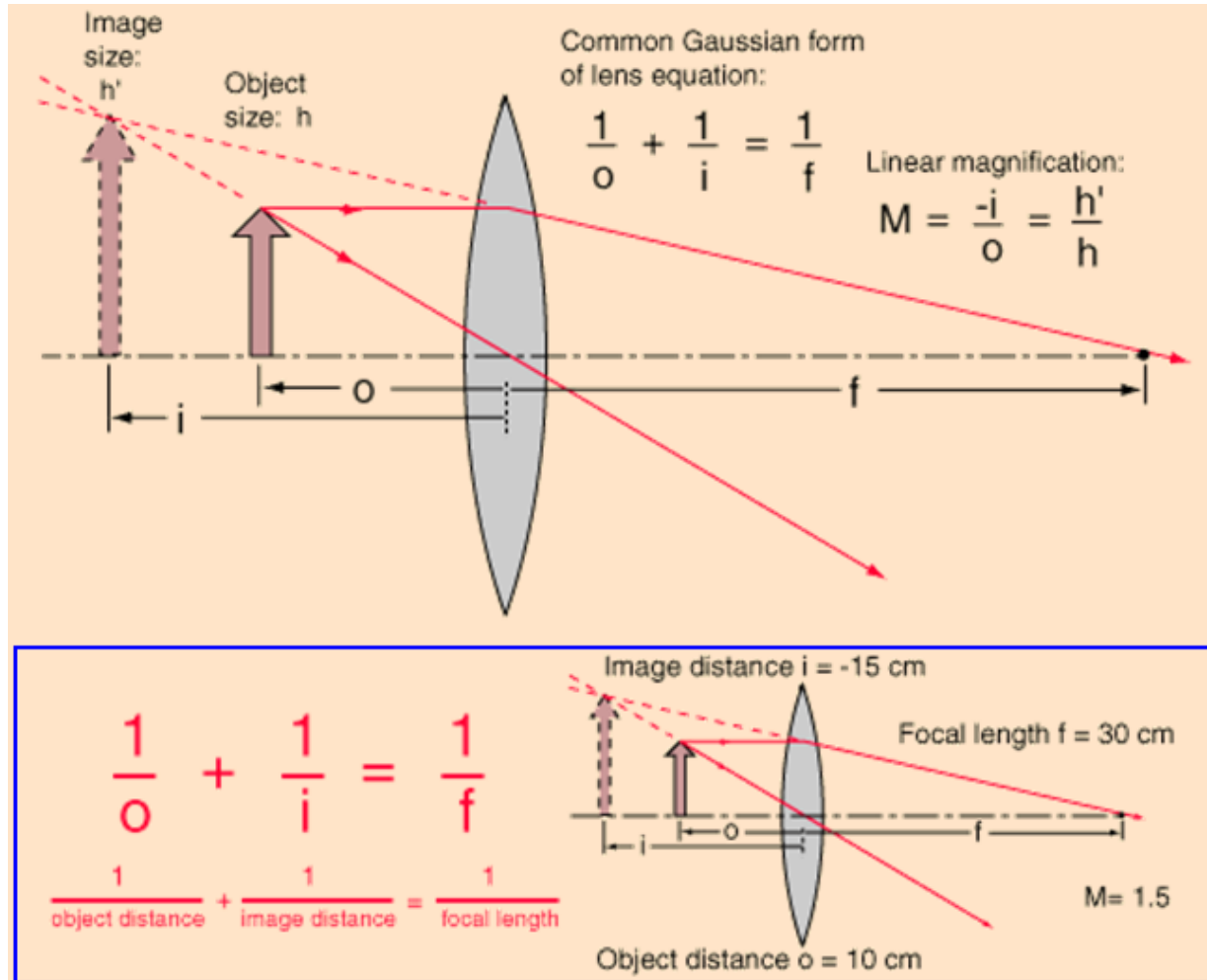
$$\frac{1}{S_1} + \frac{1}{S_2} = \frac{1}{f}$$

for  $S_1 < f$



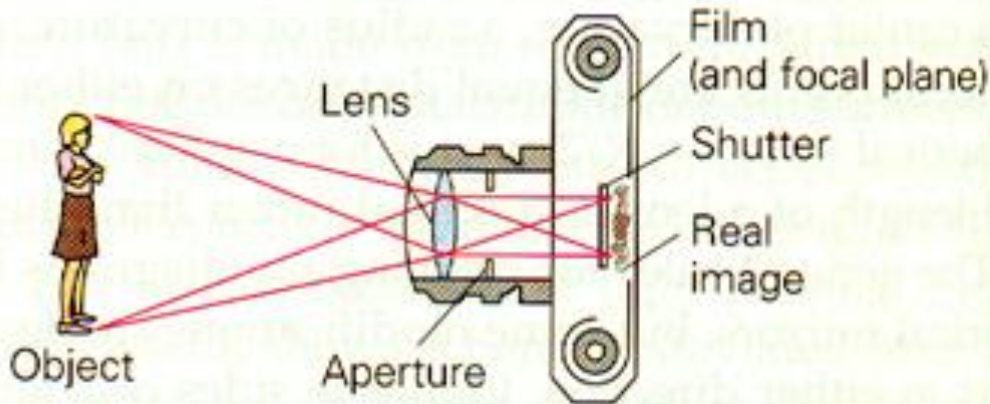
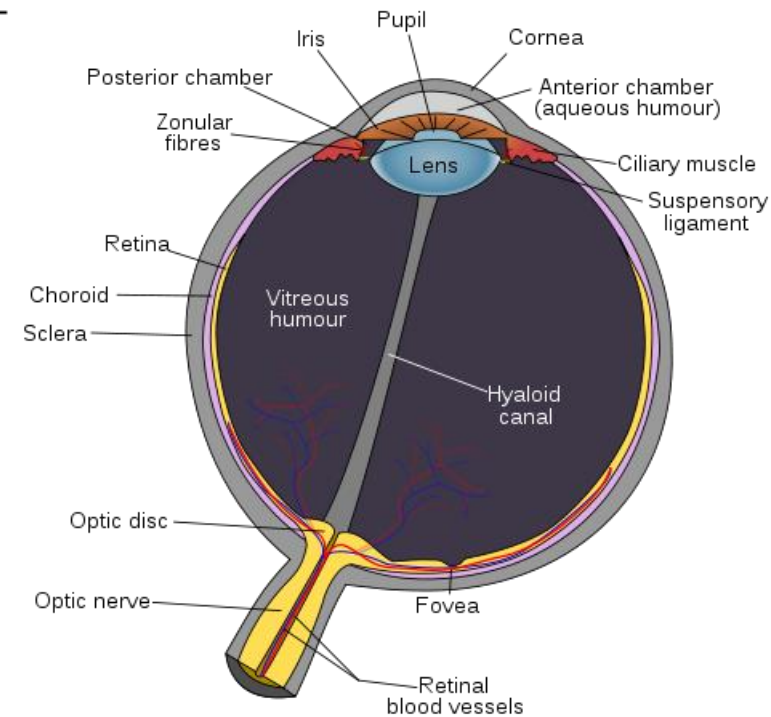
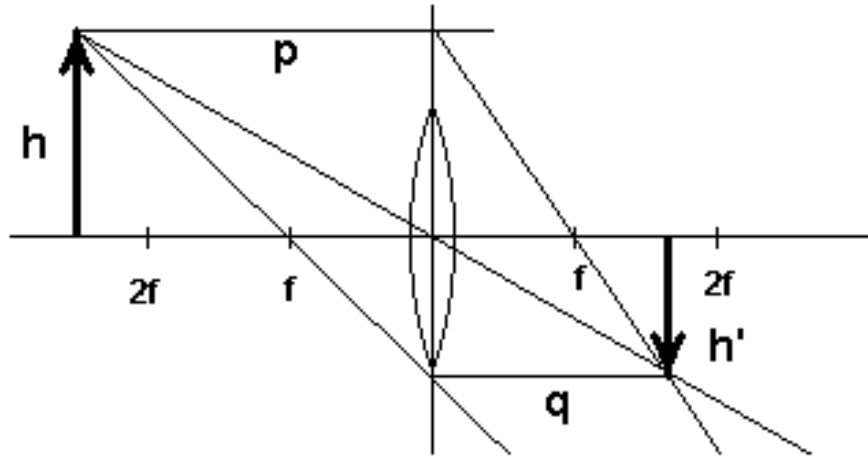
# Lenses

## Imaging properties: virtual image



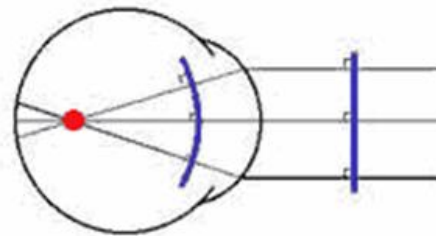
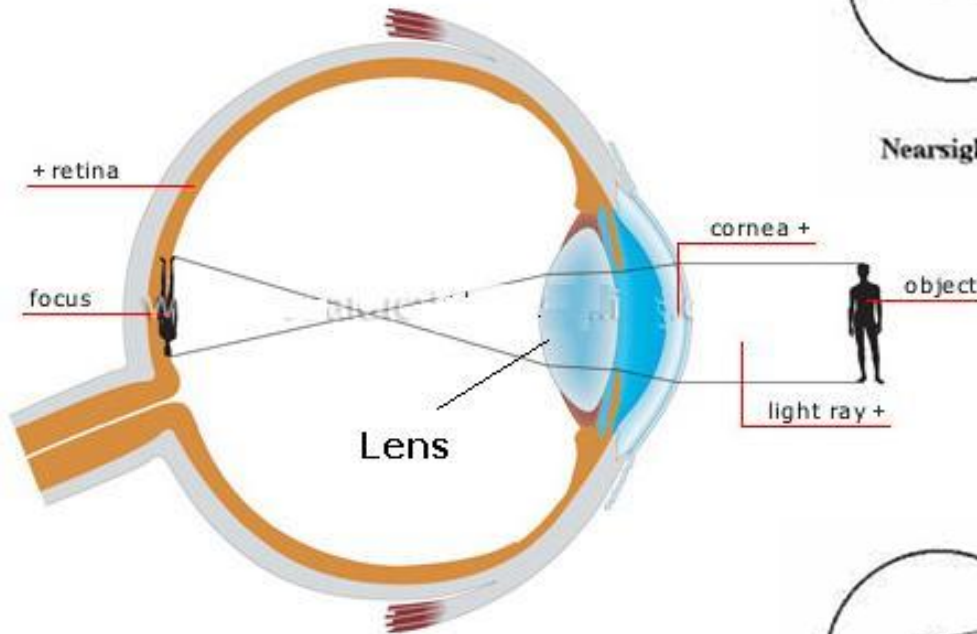
# Lenses

## Imaging properties: real image formation

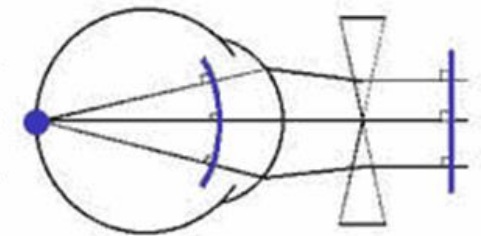


# Lenses

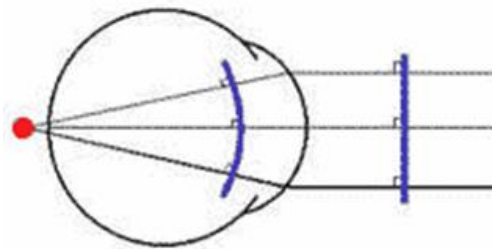
## Imaging properties: real image formation



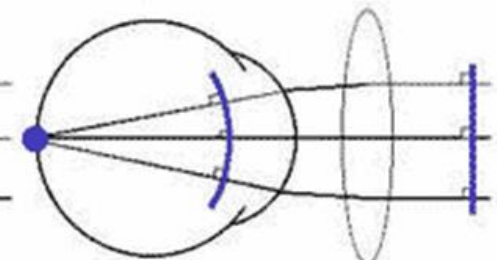
Nearsighted eye - Uncorrected



Nearsighted eye - Corrected  
with a **NEGATIVE** (diverging) lens



Farsighted eye - Uncorrected



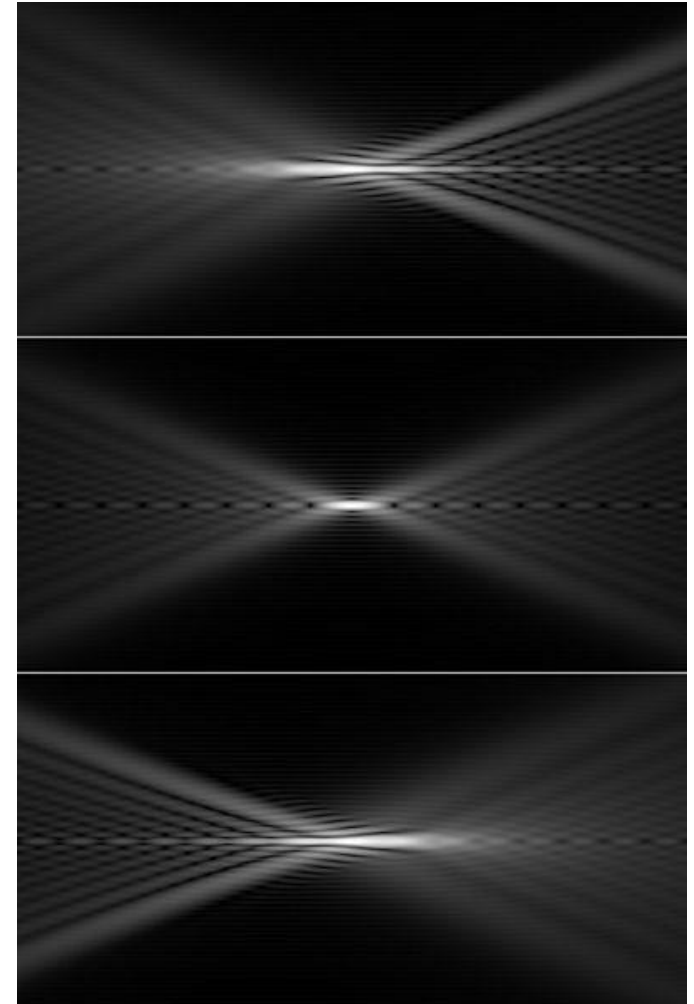
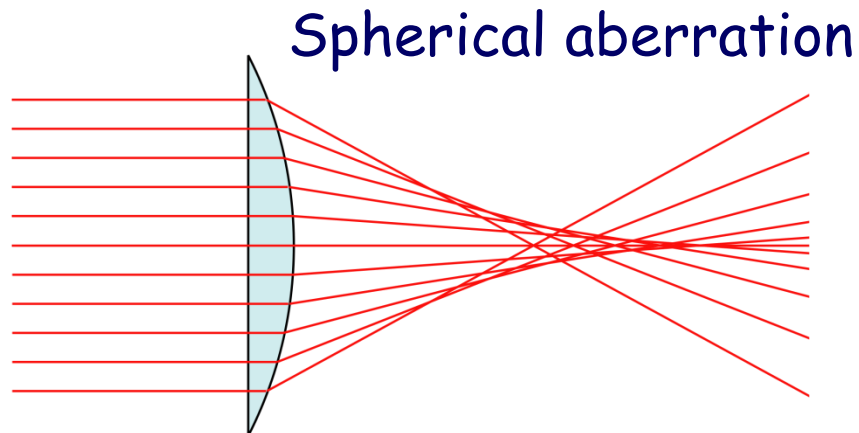
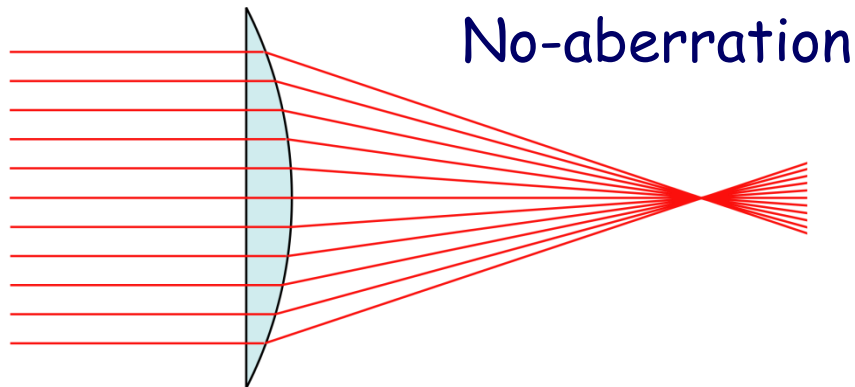
Farsighted eye - Corrected  
with a **POSITIVE** (converging) lens



# Lenses

Some optical aberrations: *spherical*

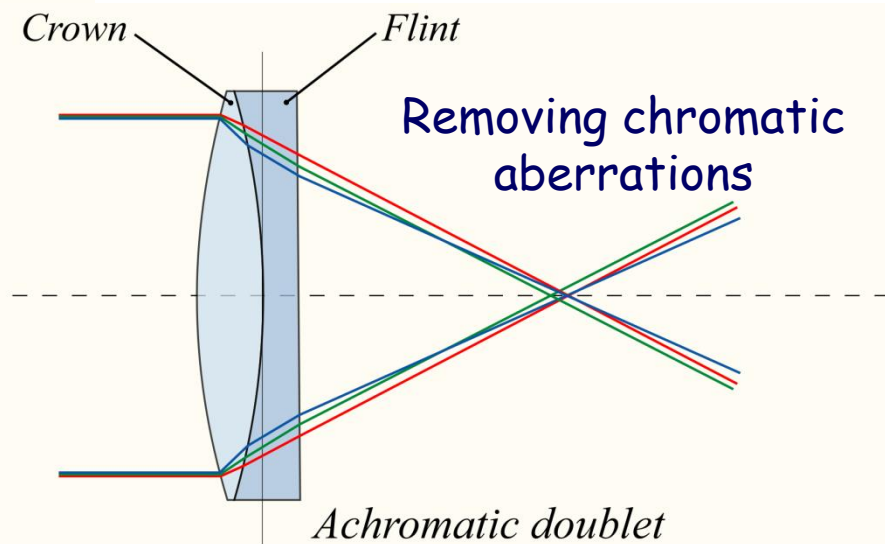
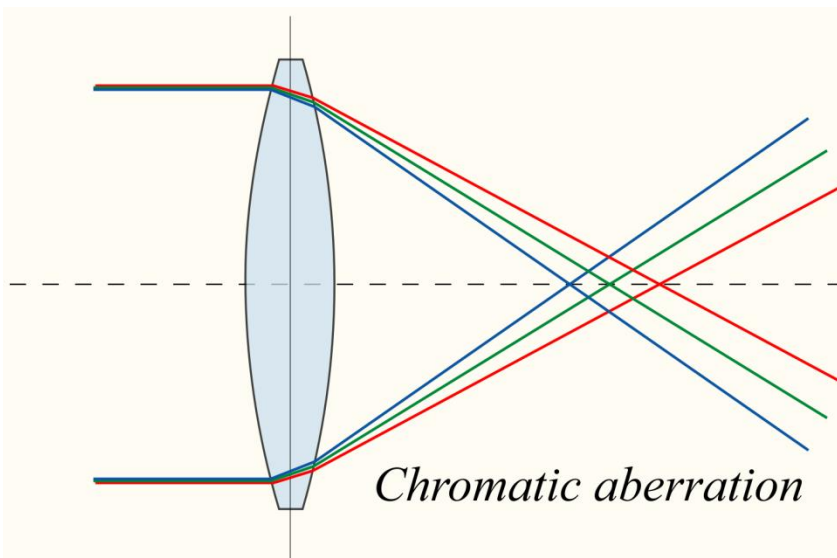
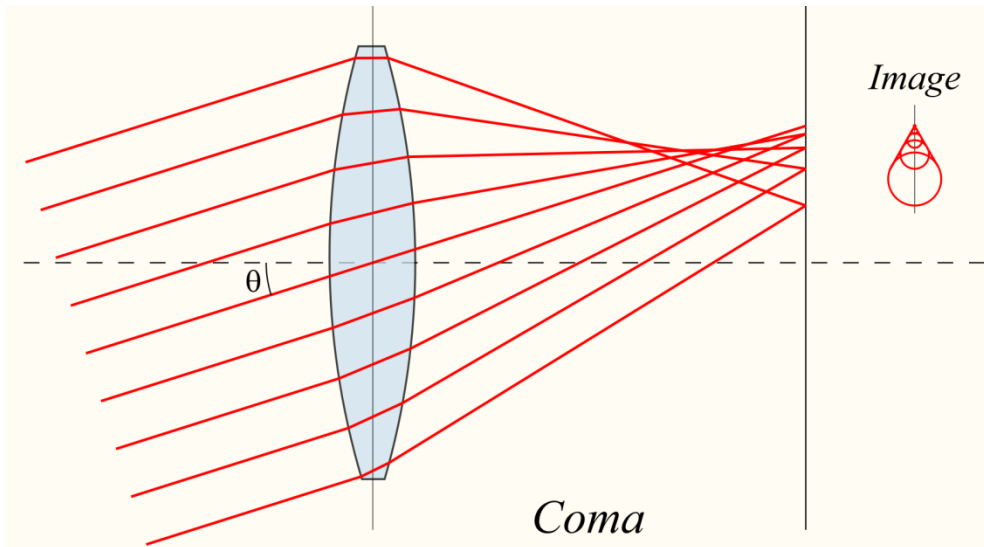
Spherical aberration





# Lenses

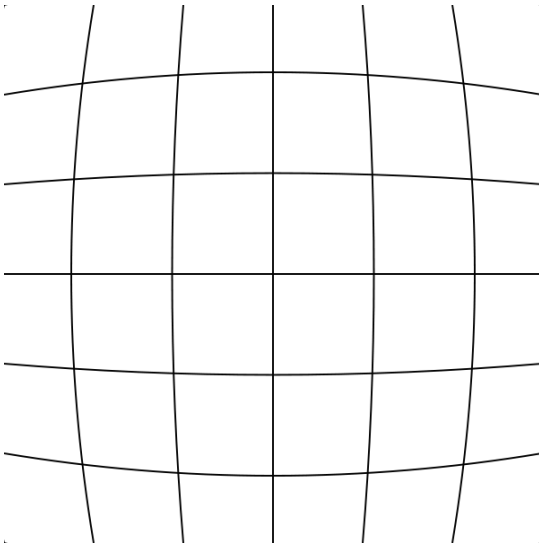
## Some optical aberrations: coma & chromatic



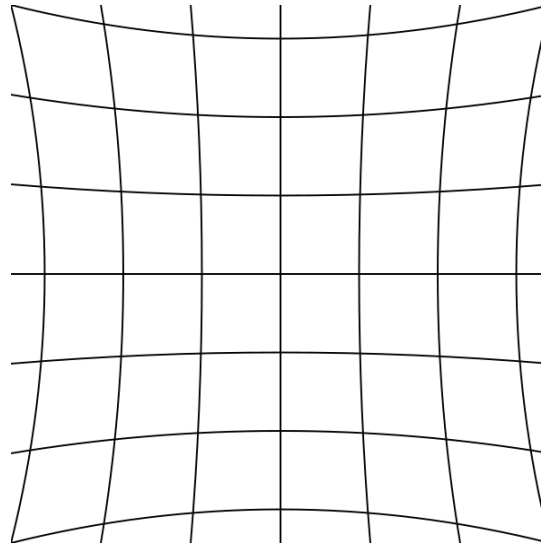
# Lenses

Some optical aberrations: *distortion (need for "camera" calibration and software)*

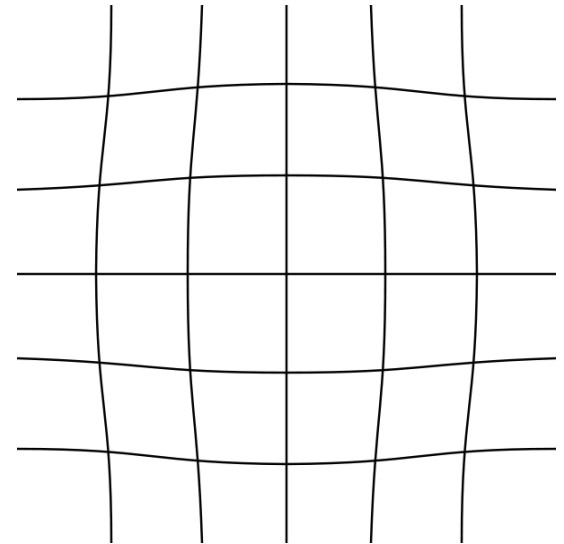
Barrel



Pincushion



Mustache



# Potential Course Projects

Overview: lab visit

- Ultra-high speed imaging: DIC
- Shearography: NDT
- Fringe Projection: Shape measurements & NDT
- MEMS metrology: Shape/deformation measurements & NDT
- Digital holography
- Other...

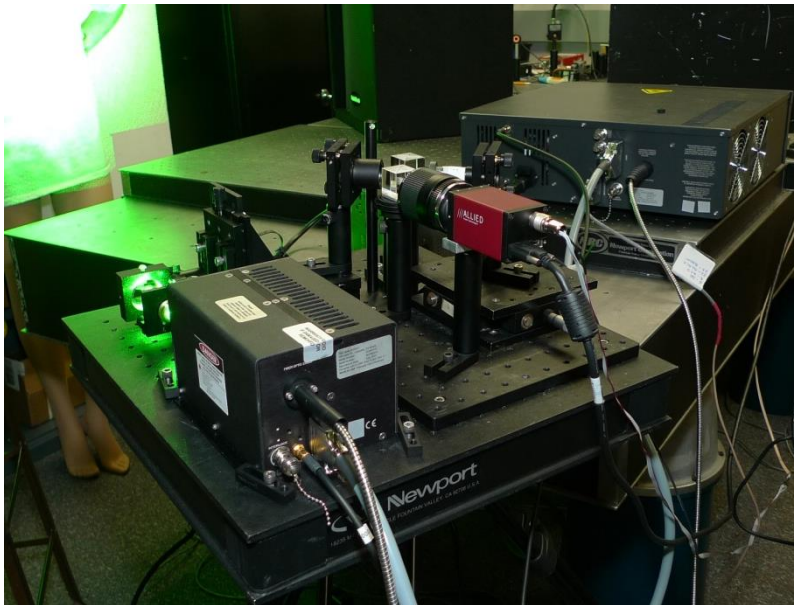


# Potential Course Projects

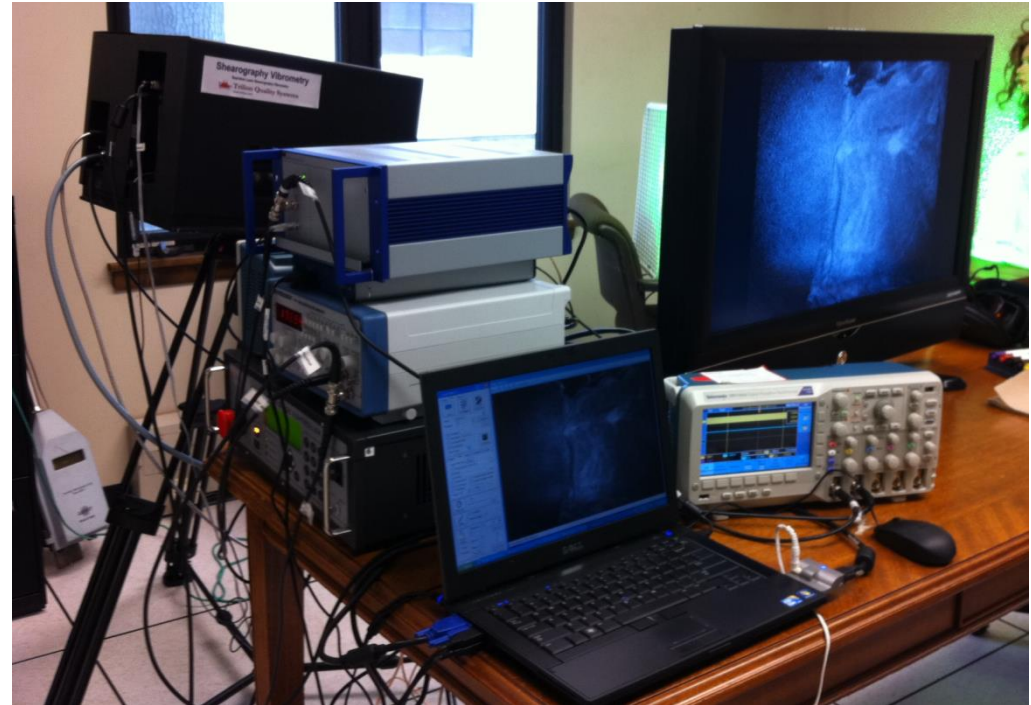
## Overview: shearography

Nondestructive testing: standoff detection  
Internal defect detection & measurements

Realized opto-electronic head with  
pulsed laser



Developed holographic system in the field

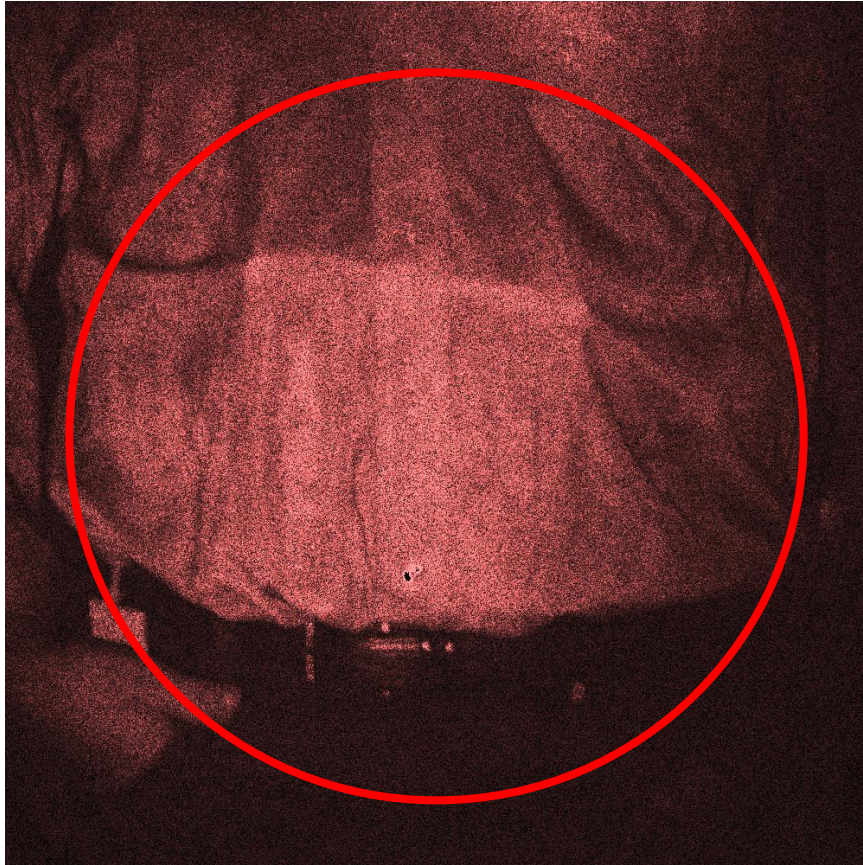




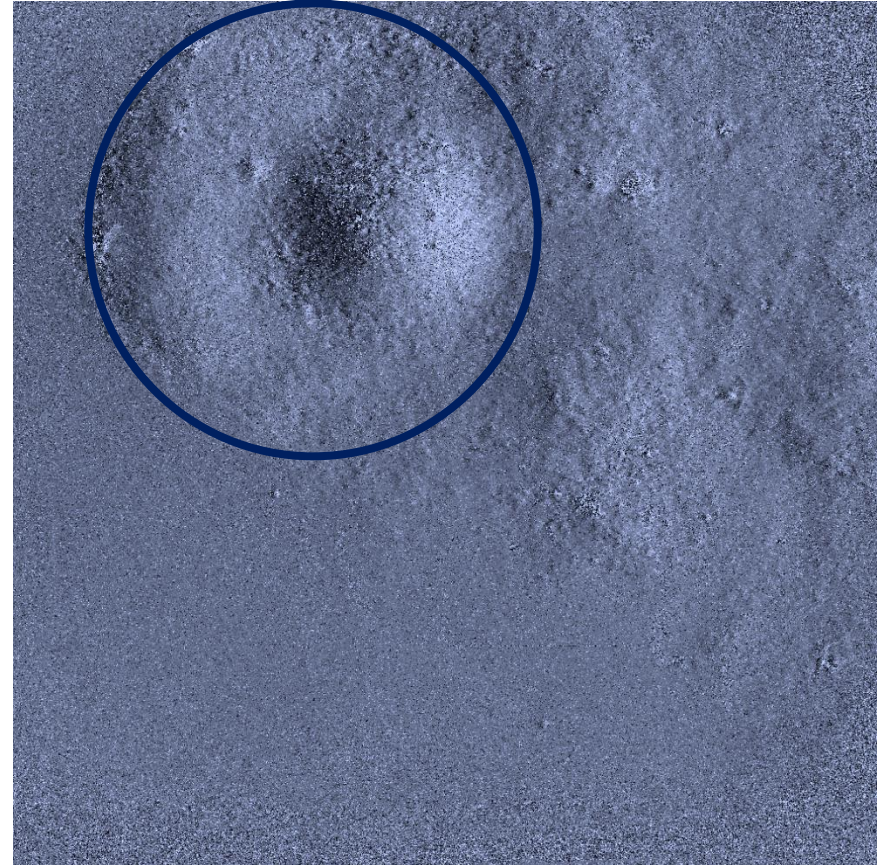
# Nondestructive testing: standoff detection

## Internal defect detection & measurements

Hidden object under person's shirt



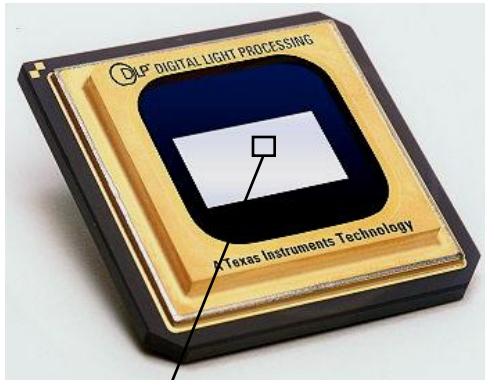
Detected defect an inside object





# Course Projects

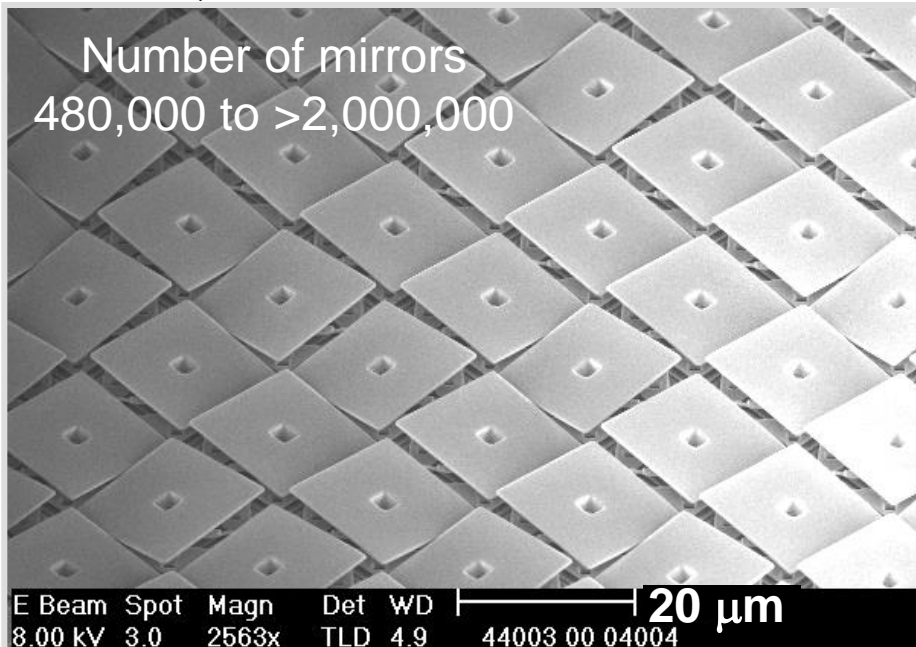
## Overview: Fringe Projection for Shape measurements & NDT



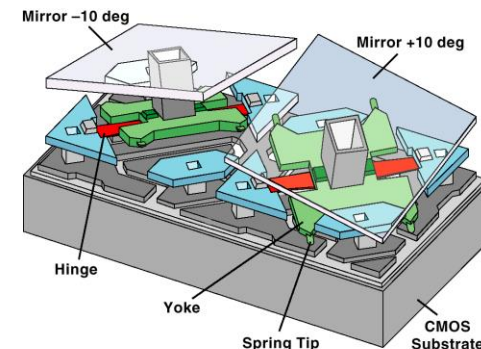
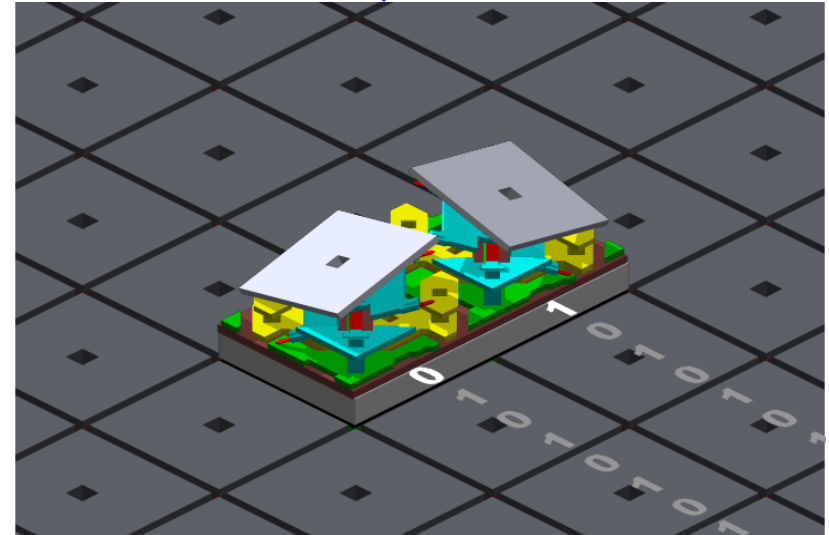
Texas  
Instrument's  
DMD

Close-up of chip surface

Number of mirrors  
480,000 to >2,000,000



Each mirror of the DMD is  
individually addressable

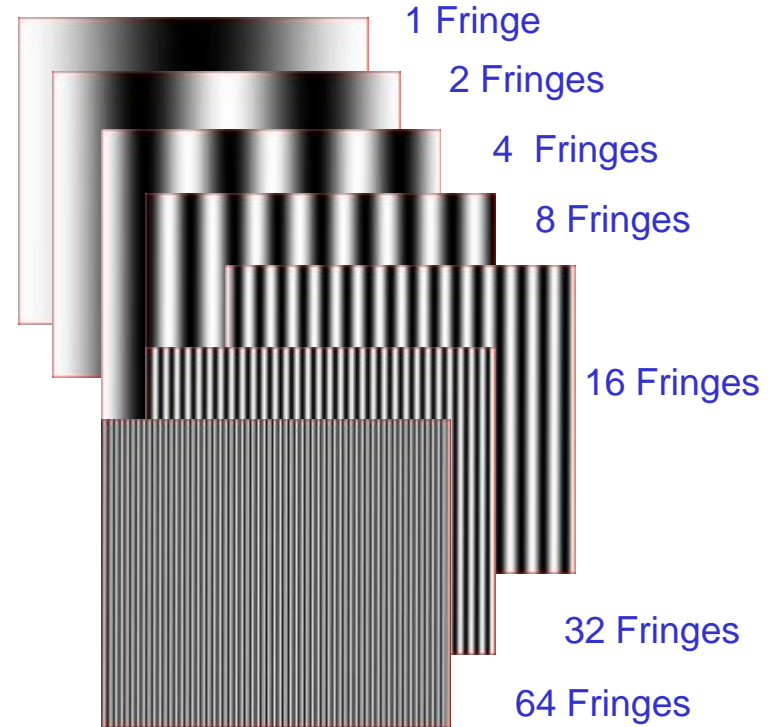
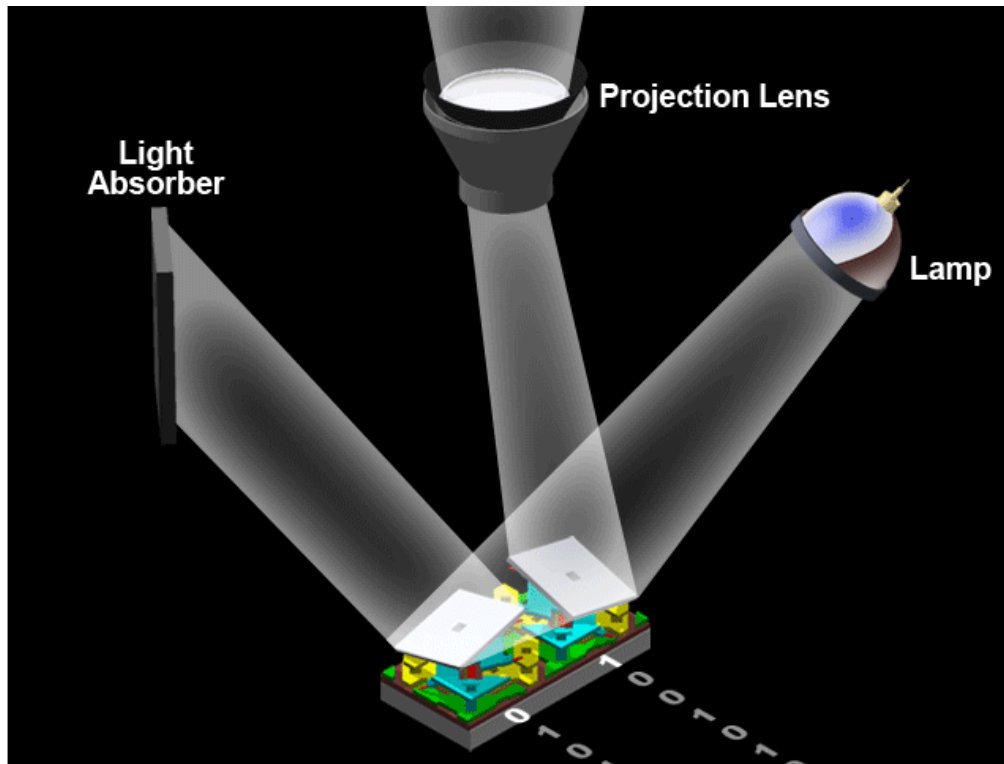




# MEMS in optoelectronic metrology

High-speed measurements based on holographic interferometry principles

Use of computer generated holograms



# MEMS in optoelectronic metrology

High-speed measurements based on holographic interferometry principles

Shape measurements in '3D  
inspection applications'

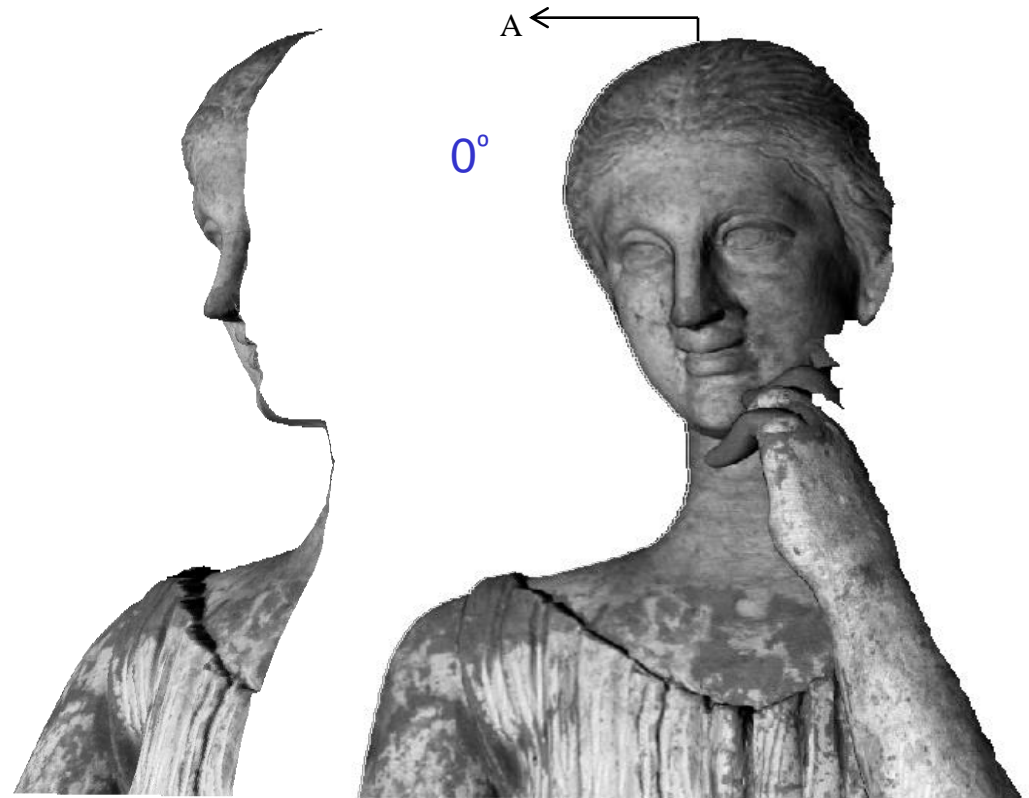


# **MEMS in optoelectronic metrology: art-conservation**

High-speed measurements based on holographic interferometry principles

Worcester Art Museum: Sculpture titled  
"Funeral of a Young Maiden" Casona,  
South Italy. Late 4<sup>th</sup> Century BCE

Representative Measurements



# MEMS in optoelectronic metrology: road shape

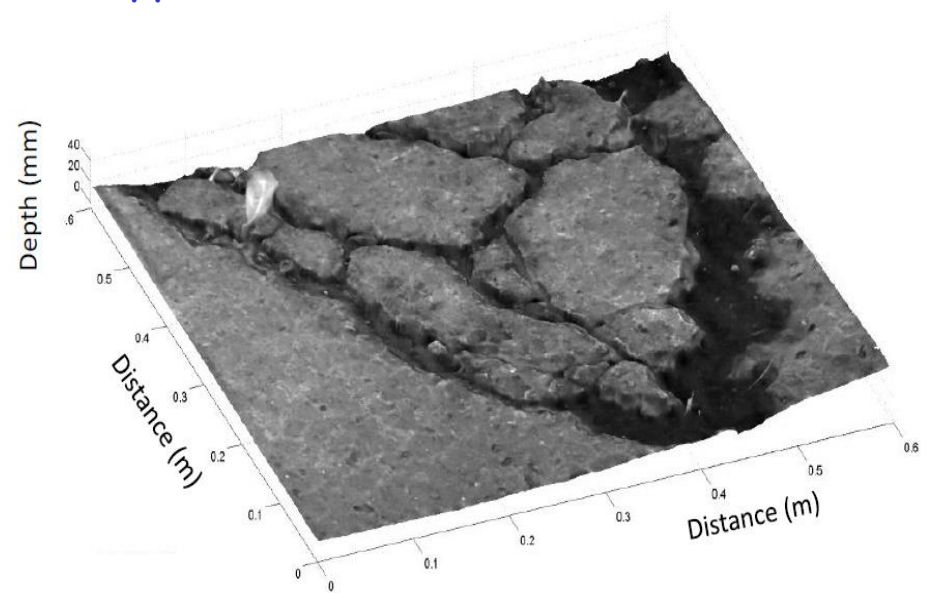
High-speed measurements based on holographic interferometry principles

- A prototype system has been developed and applied to road surface analysis
- We are currently designing a robust, low-cost, projection system that can be deployed in the field for measurements at up to 60 mph driving speeds

Prototype projector on a vehicle

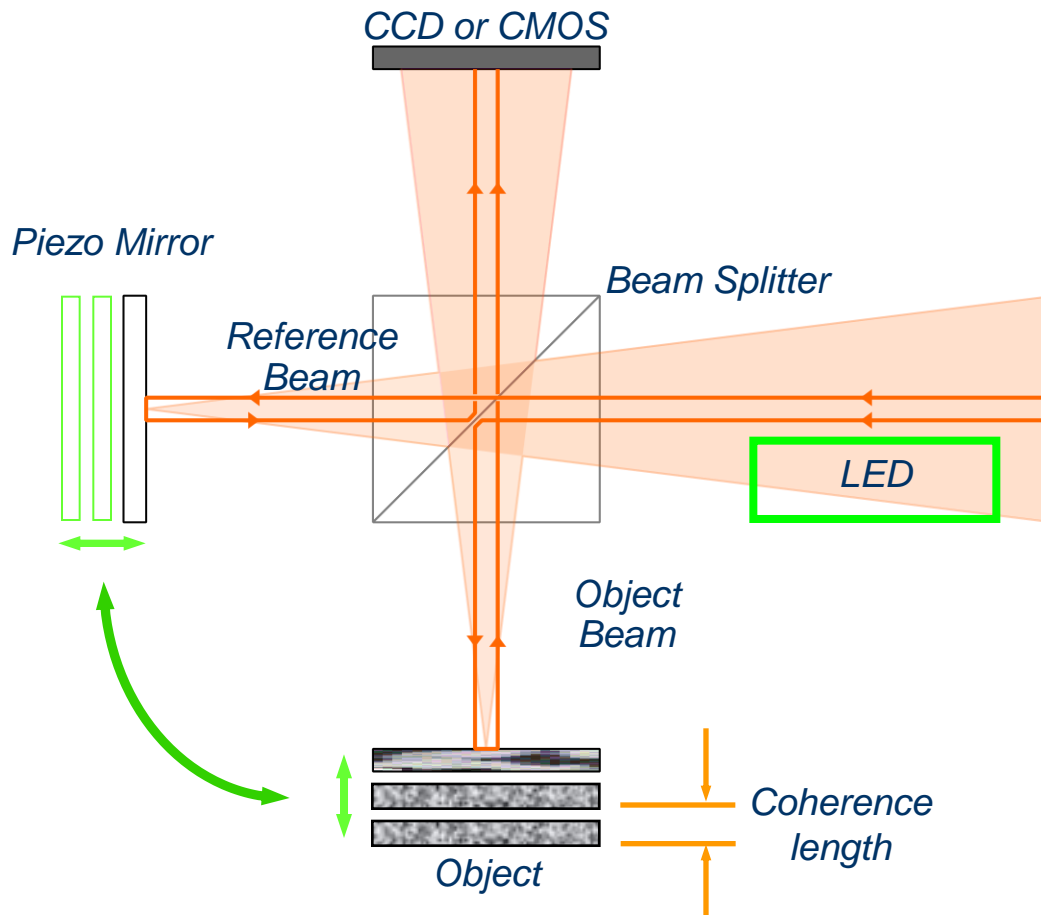


Typical surface road measurements



# Course Projects

## Overview: MEMS metrology for Shape/deformation measurements & NDT



- ❑ High-power LED's: 470, 520, 620, 680 nm
- ❑ FWHM  $\approx 25$  nm
- ❑ Coherence length:  $\approx 10 \mu\text{m}$  (620 nm)
- ❑ Matching of the OPLD within coherence length
- ❑ T and I modulation: rise and fall time of 175 nsec

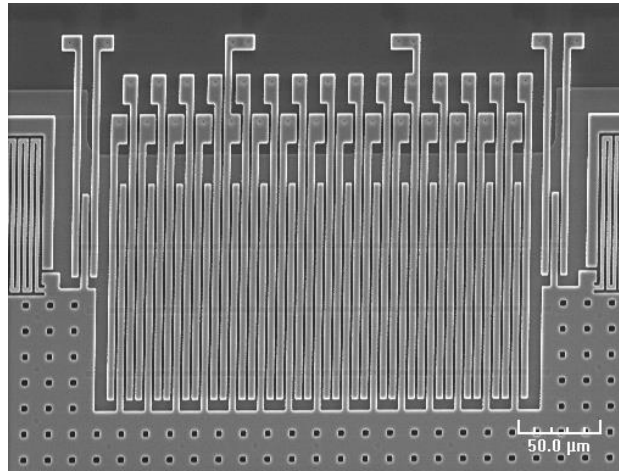
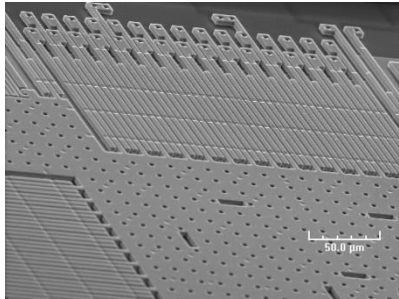




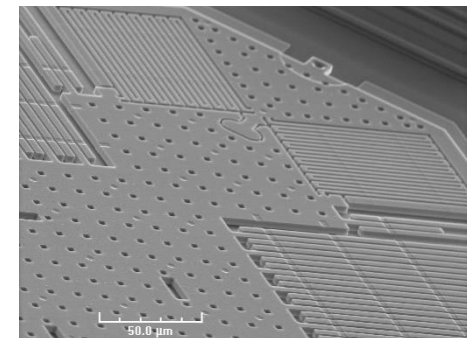
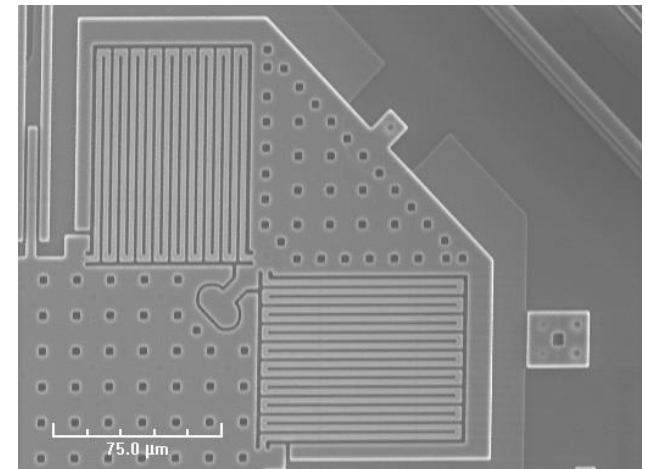
# Course Projects

## MEMS accelerometers: shape/deformation/NDT

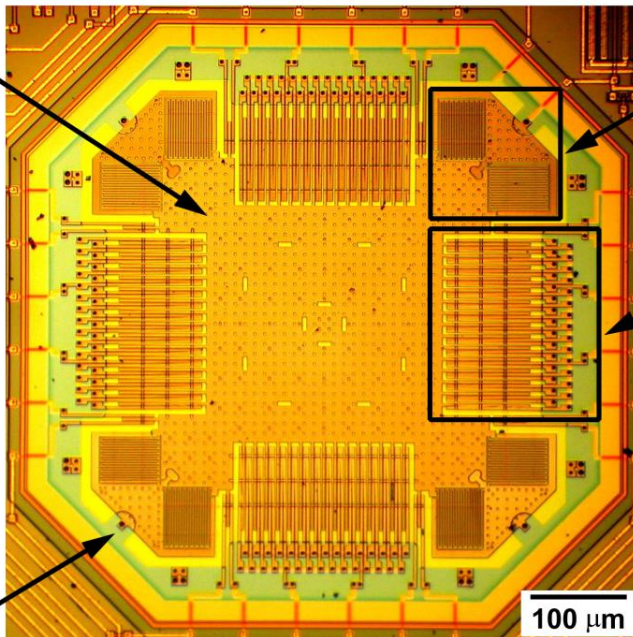
Electrostatic  
combs



Folded  
springs



Proof  
mass



4 sets,  
folded  
springs  
(dual axes)

4 sets,  
electrostatic  
combs  
(capacitive  
electrodes)

Substrate



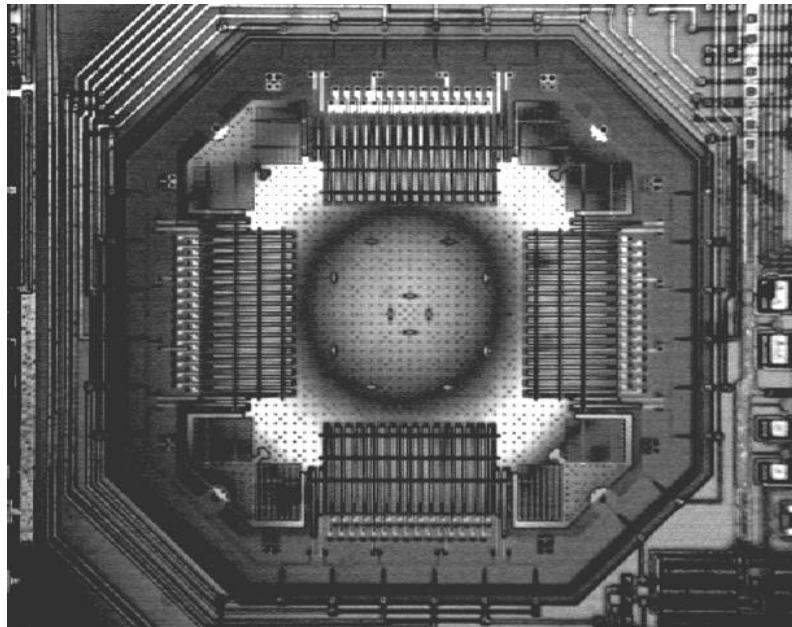


# Full-field-of-view characterization of mode shapes of vibration

Fundamental frequency is related to the measuring accuracy of the MEMS device

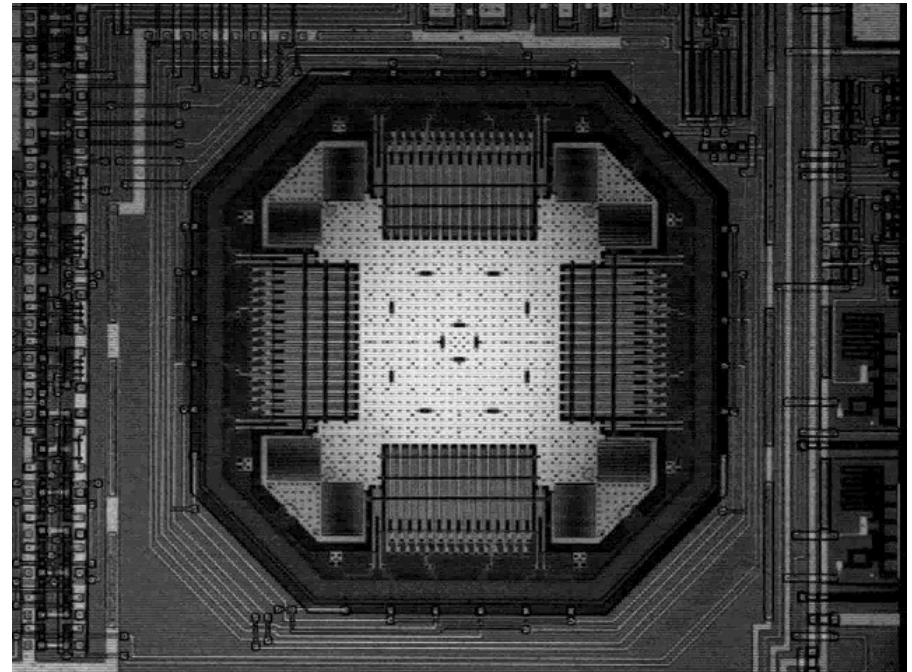
Continuous full-field-of-view measurements

Observed fundamental mode at 10.65 KHz



100 μm

Frequency scan: 10 kHz - 11 kHz



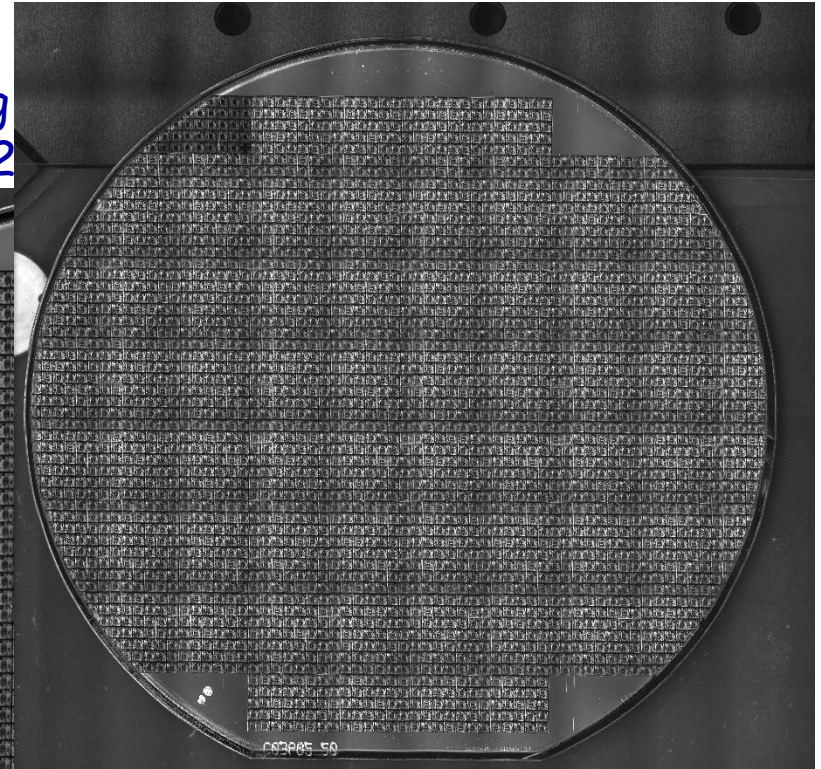
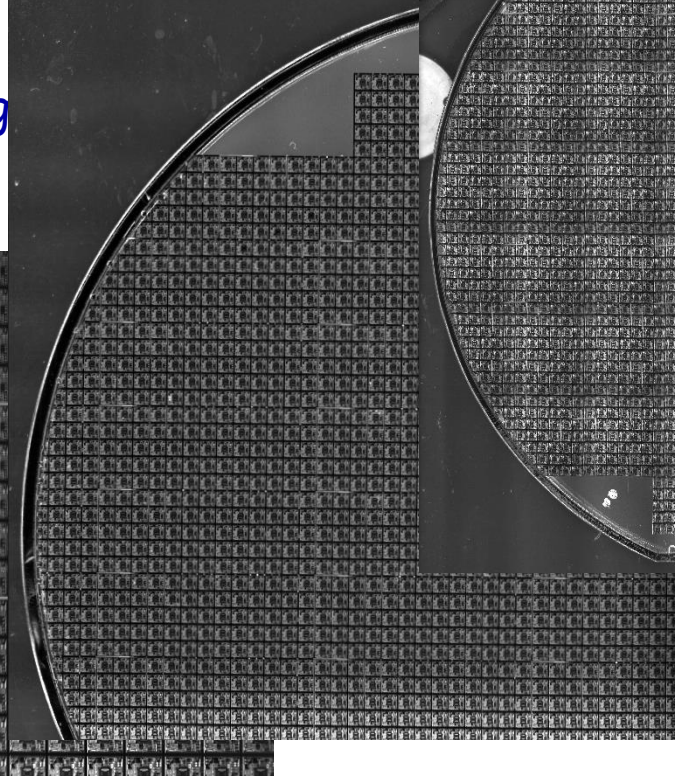
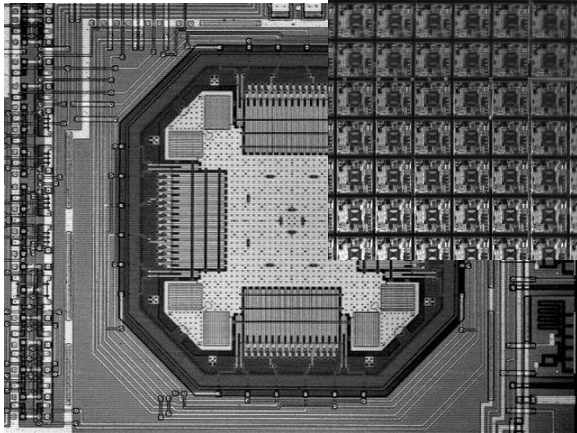
# Testing at the wafer level: inspecting an ADXL202 wafer

## Multi-scale approach

Level-3: stitching  
patches of Level-2

Level-2: stitching  
individual die  
measurements

Level-1:  
measurement  
of individual  
dies



Level-4: stitching  
patches of Level-3



# Announcements

- Homework distributed soon in class/web
- Project for this class: list of topics (CF) and teams, for example:
  - Modal analysis by (a) digital holography; (b) shearography; and (c) DIC. Modal analysis supported by analytical and computational work.

